

# **Quad- Core I ntel® Xeon® Processor 5 3 0 0 Series**

**Datasheet**

**Septem ber 2 0 0 7**

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# <span id="page-8-0"></span>**1 I ntroduction**

The Quad-Core I ntel® Xeon® Processor 5300 Series are 64-bit server/ workstation processors utilizing four Intel Core™ microarchitecture cores. These processors are based on I ntel's 65 nanom eter process technology com bining high perform ance with the power efficiencies of low-power I ntel Core™ m icroarchitecture cores. The Quad-Core I ntel® Xeon® Processor 5300 Series consists of two die, each containing two processor cores. All processors m aintain the tradition of com patibility with I A-32 software. Some key features include on-die, 32 KB Level 1 instruction data caches per core and 4 MB shared Level 2 cache per die (8 MB Total Cache per processor) with Advanced Transfer Cache Architecture. The processor's Data Prefetch Logic speculatively fetches data to the L2 cache before an L1 cache requests occurs, resulting in reduced bus cycle penalties and im proved performance. The 1333 MHz Front Side Bus (FSB) is a quad-pum ped bus running off a 333 MHz system clock, which results in 10.6 GBytes per second data transfer. The 1066 MHz Front Side Bus is based on a 266 MHz system clock for an 8.5 GBytes per second data transfer rate. The Quad-Core I ntel® Xeon® Processor X5300 Series offers higher clock frequencies than the Quad-Core I ntel® Xeon® Processor E5300 Series for platform s that are targeted for the performance optimized segm ent. The Quad-Core I ntel® Xeon® Processor L5300 Series is a lower voltage, lower power processor intended for ultra dense platform s.

Enhanced thermal and power management capabilities are implemented including Thermal Monitor 1 (TM1), Thermal Monitor 2 (TM2) and Enhanced Intel SpeedStep® Technology. TM1 and TM2 provide efficient and effective cooling in high temperature situations. Enhanced Intel SpeedStep® Technology provides power management capabilities to servers and workstations.

The Quad-Core I ntel® Xeon® Processor 5300 Series features include Advanced Dynamic Execution, enhanced floating point and multi-media units, Streaming SIMD Extensions 2 (SSE2) and Streaming SI MD Extensions 3 (SSE3). Advanced Dynamic Execution improves speculative execution and branch prediction internal to the processor. The floating point and multi-media units include 128-bit wide registers and a separate register for data movement. SSE3 instructions provide highly efficient doubleprecision floating point, SIMD integer, and memory management operations.

The Quad-Core I ntel® Xeon® Processor 5300 Series supports I ntel® 64 architecture as an enhancem ent to I ntel's I A-32 architecture. This enhancem ent allows the processor to execute operating systems and applications written to take advantage of the 64-bit extension technology. Further details on I ntel 64 architecture and its programming model can be found in the Intel® 64 and IA-32 Architecture Software Developer's Manual.

In addition, the Quad-Core Intel® Xeon® Processor 5300 Series supports the Execute Disable Bit functionality. When used in conjunction with a supporting operating system , Execute Disable allows memory to be marked as executable or non executable. This feature can prevent some classes of viruses that exploit buffer overrun vulnerabilities and can thus help improve the overall security of the system. Further details on Execute Disable can be found at http: / / www.intel.com/ cd/ ids/ developer/ asmo-na/ eng/ 149308.htm.

The Quad-Core I ntel® Xeon® Processor 5300 Series supports I ntel® Virtualization Technology for hardware-assisted virtualization within the processor. I ntel Virtualization Technology is a set of hardware enhancements that can im prove virtualization solutions. Intel Virtualization Technology is used in conjunction with Virtual Machine



Monitor software enabling m ultiple, independent software environm ents inside a single platform . Further details on I ntel Virtualization Technology can be found at http: / / developer.intel.com/ technology/ vt.

The Quad-Core I ntel® Xeon® Processor 5300 Series are intended for high performance server and workstation systems. The processors support a Dual Independent Bus (DIB) architecture with one processor on each bus, up to two processor sockets in a system . The DIB architecture provides improved performance by allowing increased FSB speeds and bandwidth. The processors will be packaged in an FC-LGA6 Land Grid Array package with 771 lands for improved power delivery. It utilizes a surface mount LGA771 socket that supports Direct Socket Loading (DSL).

## <span id="page-9-0"></span>**Table 1 - 1 . Quad- Core I ntel® Xeon® Processor 5 3 0 0 Series Features**



Quad-Core Intel® Xeon® Processor 5300 Series based platforms implement independent core voltage ( $V_{CC}$ ) power planes for each processor. FSB termination voltage ( $V_{TT}$ ) is shared and must connect to all FSB agents. The processor core voltage utilizes power delivery guidelines specified by VRM/ EVRD 11.0 and its associated load line (see Voltage Regulator Module (VRM) and Enterprise Voltage Regulator-Down (EVRD) 11.0 Design Guidelines for further details). VRM/ EVRD 11.0 will support the power requirem ents of all frequencies of the processors including Flexible Motherboard Guidelines (FMB) (see [Section 2.13.1\)](#page-26-4). Refer to the appropriate platform design guidelines for im plementation details.

The Quad-Core I ntel® Xeon® Processor 5300 Series support 1333, or 1066 MHz Front Side Bus operation. The FSB utilizes a split-transaction, deferred reply protocol and Source-Synchronous Transfer (SST) of address and data to improve performance. The processor transfers data four tim es per bus clock (4X data transfer rate, as in AGP 4X). Along with the 4X data bus, the address bus can deliver addresses two times per bus clock and is referred to as a 'double-clocked' or a 2X address bus. In addition, the Request Phase completes in one clock cycle. Working together, the 4X data bus and 2X address bus provide a data bus bandwidth of up to 10.66 GBytes (1333 MHz), or 8.5 GBytes (1066 MHz) per second. The FSB is also used to deliver interrupts.

Signals on the FSB use Assisted Gunning Transceiver Logic (AGTL+ ) level voltages. [Section 2.1](#page-14-2) contains the electrical specifications of the FSB while im plementation details are fully described in the appropriate platform design guidelines (refer to [Section 1.3](#page-12-1)).



# <span id="page-10-0"></span>**1 .1 Term inology**

A '#' symbol after a signal name refers to an active low signal, indicating a signal is in the asserted state when driven to a low level. For exam ple, when RESET# is low, a reset has been requested. Conversely, when NMI is high, a nonmaskable interrupt has occurred. In the case of signals where the name does not imply an active state but describes part of a binary sequence (such as *address* or *data*), the '#' symbol implies that the signal is inverted. For example,  $D[3:0] = 'HLHL'$  refers to a hex 'A', and  $D[3:0]$ # = 'LHLH' also refers to a hex 'A' (H= High logic level, L= Low logic level).

Commonly used terms are explained here for clarification:

- **Quad- Core I ntel® Xeon® Processor 5 3 0 0 Series**  I ntel 64-bit microprocessor intended for dual processor servers and workstations. The Quad-Core Intel® Xeon® Processor 5300 Series is based on I ntel's 65 nanom eter process, in the FC-LGA6 package with four processor cores. For this docum ent, "processor" is used as the generic term for the "Quad-Core I ntel® Xeon® Processor 5300 Series". The term 'processors' and "Quad-Core I ntel® Xeon® Processor 5300 Series" are inclusive of Quad-Core I ntel® Xeon® Processor E5300 Series, Quad-Core I ntel® Xeon® Processor X5300 Series and Quad-Core I ntel® Xeon® Processor L5300 Series.
- **Quad- Core I ntel® Xeon® Processor E5 3 0 0 Series**  A mainstream performance version of the Quad-Core I ntel® Xeon® Processor 5300 Series. For this document "Quad-Core Intel® Xeon® Processor E5300 Series" is used to call out specifications that are unique to the Quad-Core I ntel® Xeon® Processor E5300 Series SKU.
- **Quad- Core I ntel® Xeon® Processor X5 3 0 0 Series**  An accelerated performance version of the Quad-Core I ntel® Xeon® Processor 5300 Series. For this document "Quad-Core Intel® Xeon® Processor X5300 Series" is used to call out specifications that are unique to the Quad-Core I ntel® Xeon® Processor X5300 Series SKU.
- **Quad- Core I ntel® Xeon® Processor X5 3 6 5 Series** An ultra perform ance version of the Quad-Core I ntel® Xeon® Processor 5300 Series. For this docum ent "Quad-Core I ntel® Xeon® Processor X5365 Series" is used to call out specifications that are unique to the Quad-Core Intel® Xeon® Processor X5365 Series SKU.
- **Quad- Core I ntel® Xeon® Processor L5 3 0 0 Series** I ntel 64-bit m icroprocessor intended for dual processor server blades and em bedded servers. The Quad-Core I ntel® Xeon® Processor L5300 Series is a lower voltage, lower power version of the Quad-Core I ntel® Xeon® Processor 5300 Series. For this document "Quad-Core I ntel® Xeon® Processor L5300 Series" is used to call out specifications that are unique to the Quad-Core I ntel® Xeon® Processor L5300 Series.
- **Quad- Core I ntel® Xeon**® **Processor L5 3 1 8**  I ntel 64-bit microprocessor intended for dual processor server blades and embedded servers requiring higher case tem peratures. The Quad-Core I ntel® Xeon® Processor L5318 is a lower voltage, lower power version of the Quad-Core I ntel® Xeon® Processor 5300 Series. For this docum ent "Quad-Core I ntel® Xeon® Processor L5318" is used to call out specifications that are unique to the Quad-Core I ntel® Xeon® Processor L5318 SKU.
- FC-LGA6 (Flip Chip Land Grid Array) Package The Quad-Core Intel<sup>®</sup> Xeon<sup>®</sup> Processor 5300 Series package is a Land Grid Array, consisting of a processor core m ounted on a pinless substrate with 771 lands, and includes an integrated heat spreader (IHS).

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- **LGA7 7 1 socket**  The Quad-Core I ntel® Xeon® Processor 5300 Series interfaces to the baseboard through this surface mount, 771 Land socket. See the LGA771 Socket Design Guidelines for details regarding this socket.
- **Processor core**  Processor core with integrated L1 cache. L2 cache and system bus interface are shared between the two cores on the die. All AC tim ing and signal integrity specifications are at the pads of the processor die.
- **FSB ( Front Side Bus)**  The electrical interface that connects the processor to the chipset. Also referred to as the processor system bus or the system bus. All memory and I/O transactions as well as interrupt messages pass between the processor and chipset over the FSB.
- **Dual I ndependent Bus ( DI B)** A front side bus architecture with one processor on each bus, rather than a FSB shared between two processor agents. The DIB architecture provides im proved perform ance by allowing increased FSB speeds and bandwidth.
- **Flexible Motherboard Guidelines ( FMB)**  Are estimates of the maxim um values the Quad-Core Intel® Xeon® Processor 5300 Series will have over certain time periods. The values are only estimates and actual specifications for future processors m ay differ.
- **Functional Operation** Refers to the norm al operating conditions in which all processor specifications, including DC, AC, FSB, signal quality, mechanical and therm al are satisfied.
- **Storage Conditions** Refers to a non-operational state. The processor m ay be installed in a platform, in a tray, or loose. Processors may be sealed in packaging or exposed to free air. Under these conditions, processor lands should not be connected to any supply voltages, have any I/Os biased or receive any clocks. Upon exposure to "free air" (that is, unsealed packaging or a device rem oved from packaging m aterial) the processor m ust be handled in accordance with m oisture sensitivity labeling (MSL) as indicated on the packaging material.
- **Priority Agent**  The priority agent is the host bridge to the processor and is typically known as the chipset.
- **Symmetric Agent** A symmetric agent is a processor which shares the same I/O subsystem and memory array, and runs the same operating system as another processor in a system. Systems using symmetric agents are known as Symmetric Multiprocessing (SMP) system s.
- **Integrated Heat Spreader (IHS)** A component of the processor package used to enhance the thermal perform ance of the package. Com ponent therm al solutions interface with the processor at the IHS surface.
- **Therm al Design Pow er** Processor therm al solutions should be designed to m eet this target. It is the highest expected sustainable power while running known power intensive real applications. TDP is not the m axim um power that the processor can dissipate.
- **Intel<sup>®</sup> 64 Architecture** Instruction set architecture and programming environment of Intel's 64-bit processors, which are a superset of and compatible with IA-32. This 64-bit instruction set architecture was formerly known as IA-32 with EM64T or Intel® EM64T.
- **Enhanced I ntel SpeedStep**® **Technology** Technology that provides power m anagem ent capabilities to servers and workstations.
- **Platform Environm ent Control I nterface ( PECI )** A proprietary one-wire bus interface that provides a comm unication channel between I ntel processor and chipset com ponents to external therm al m onitoring devices, for use in fan speed control. PECI communicates readings from the processor's Digital Thermal Sensor (DTS). The replaces the thermal diode available in previous processors.



- **I ntel**® **Virtualization Technology ( I ntel® VT)**  Processor virtualization which when used in conjunction with Virtual Machine Monitor software enables multiple, robust independent software environments inside a single platform.
- **VRM ( Voltage Regulator Module)**  DC-DC converter built onto a module that interfaces with a card edge socket and supplies the correct voltage and current to the processor based on the logic state of the processor VID bits.
- **EVRD ( Enterprise Voltage Regulator Dow n)**  DC-DC converter integrated onto the system board that provides the correct voltage and current to the processor based on the logic state of the processor VID bits.
- **V<sub>CC</sub>** The processor core power supply.
- **V<sub>SS</sub>** The processor ground.
- V<sub>TT</sub> FSB termination voltage. (Note: In some Intel processor EMTS documents,  $V_{TT}$  is instead called  $V_{CCP}$ )

# <span id="page-12-0"></span>**1 .2 State of Data**

<span id="page-12-2"></span>The data contained within this document is the m ost accurate inform ation available by the publication date of this docum ent.

# <span id="page-12-1"></span>**1 .3 References**

Material and concepts available in the following docum ents m ay be beneficial when reading this docum ent:







Notes: Contact your Intel representative for the latest revision of these documents.

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# <span id="page-14-0"></span>**2 Electrical Specifications**

# <span id="page-14-1"></span>**2 .1 Front Side Bus and GTLREF**

<span id="page-14-2"></span>Most Quad-Core I ntel® Xeon® Processor 5300 Series FSB signals use Assisted Gunning Transceiver Logic (AGTL+ ) signaling technology. This technology provides im proved noise m argins and reduced ringing through low voltage swings and controlled edge rates. AGTL+ buffers are open-drain and require pull-up resistors to provide the high logic level and termination. AGTL+ output buffers differ from GTL+ buffers with the addition of an active PMOS pull-up transistor to "assist" the pull-up resistors during the first clock of a low-to-high voltage transition. Platform s im plem ent a term ination voltage level for AGTL+ signals defined as  $V<sub>TT</sub>$ . Because platforms implement separate power planes for each processor (and chipset), separate  $V_{CC}$  and  $V_{TT}$  supplies are necessary. This configuration allows for im proved noise tolerance as processor frequency increases. Speed enhancements to data and address buses have made signal integrity considerations and platform design methods even more critical than with previous processor families. Design guidelines for the processor FSB are detailed in the appropriate platform design guidelines (refer to [Section 1.3\)](#page-12-2).

The AGTL+ inputs require reference voltages (GTLREF\_DATA\_MID, GTLREF\_DATA\_END, GTLREF\_ADD\_MID and GTLREF\_ADD\_END) which are used by the receivers to determine if a signal is a logical 0 or a logical 1. GTLREF\_DATA\_MID and GTLREF\_DATA\_END are used for the 4X front side bus signaling group and GTLREF\_ADD\_MID and GTLREF\_ADD\_END are used for the 2X and common clock front side bus signaling groups. GTLREF\_DATA\_MID, GTLREF\_DATA\_END, GTLREF\_ADD\_MID, and GTLREF\_ADD\_END must be generated on the baseboard (See [Table 2-20](#page-41-0) for GTLREF\_DATA\_MID, GTLREF\_DATA\_END, GTLREF\_ADD\_MID and GTLREF\_ADD\_END specifications). Refer to the applicable platform design guidelines for details. Termination resistors  $(R_{TT})$  for AGTL+ signals are provided on the processor silicon and are terminated to  $V_{TT}$ . The on-die termination resistors are always enabled on the processor to control reflections on the transmission line. I ntel chipsets also provide on-die termination, thus eliminating the need to terminate the bus on the baseboard for m ost AGTL+ signals.

Some FSB signals do not include on-die termination  $(R_{TT})$  and must be terminated on the baseboard. See [Table 2-7](#page-22-0) and [Table 2-8](#page-22-1) for details regarding these signals.

The AGTL+ bus depends on incident wave switching. Therefore, tim ing calculations for AGTL+ signals are based on flight time as opposed to capacitive deratings. Analog signal simulation of the FSB, including trace lengths, is highly recommended when designing a system . Contact your I ntel Field Representative to obtain the applicable signal integrity m odels, which includes buffer and package models.



# <span id="page-15-0"></span>**2 .2 Pow er and Ground Lands**

For clean on-chip processor core power distribution, the processor has 223  $V_{\text{CC}}$  (power) and 267  $V_{SS}$  (ground) inputs. All  $V_{CC}$  lands must be connected to the processor power plane, while all  $V_{SS}$  lands must be connected to the system ground plane. The processor  $V_{CC}$  lands must be supplied with the voltage determined by the processor **Voltage I Dentification (VID) signals. See [Table 2-3](#page-19-0) for VID definitions.** 

Twenty two lands are specified as  $V_{T}$ , which provide termination for the FSB and provides power to the I/O buffers. The platform must implement a separate supply for these lands which meets the  $V_{TT}$  specifications outlined in [Table 2-12](#page-26-2).

# <span id="page-15-1"></span>**2 .3 Decoupling Guidelines**

Due to its large num ber of transistors and high internal clock speeds, the processor is capable of generating large average current swings between low and full power states. This may cause voltages on power planes to sag below their minimum values if bulk decoupling is not adequate. Larger bulk storage  $(C_{\text{BULK}})$ , such as electrolytic capacitors, supply current during longer lasting changes in current dem and by the component, such as coming out of an idle condition. Similarly, they act as a storage well for current when entering an idle condition from a running condition. Care must be taken in the baseboard design to ensure that the voltage provided to the processor remains within the specifications listed in [Table 2-12](#page-26-2). Failure to do so can result in timing violations or reduced lifetime of the component. For further information and guidelines, refer to the appropriate platform design guidelines.

# <span id="page-15-2"></span>**2.3.1 V**<sub>CC</sub> Decoupling

Vcc regulator solutions need to provide bulk capacitance with a low Effective Series Resistance (ESR), and the baseboard designer must assure a low interconnect resistance from the regulator (EVRD or VRM pins) to the LGA771 socket. Bulk decoupling must be provided on the baseboard to handle large current swings. The power delivery solution must insure the voltage and current specifications are met (as defined in [Table 2-12](#page-26-2)). For further inform ation regarding power delivery, decoupling and layout guidelines, refer to the appropriate platform design guidelines.

# <span id="page-15-3"></span>2.3.2  $V_{TT}$  **Decoupling**

Bulk decoupling m ust be provided on the baseboard. Decoupling solutions m ust be sized to meet the expected load. To insure optimal performance, various factors associated with the power delivery solution must be considered including regulator type, power plane and trace sizing, and component placement. A conservative decoupling solution consists of a com bination of low ESR bulk capacitors and high frequency ceram ic capacitors. For further inform ation regarding power delivery, decoupling and layout guidelines, refer to the appropriate platform design guidelines.



# <span id="page-16-0"></span>**2 .3 .3 Front Side Bus AGTL+ Decoupling**

The processor integrates signal term ination on the die, as well as a portion of the required high frequency decoupling capacitance on the processor package. However, additional high frequency capacitance must be added to the baseboard to properly decouple the return currents from the FSB. Bulk decoupling must also be provided by the baseboard for proper AGTL+ bus operation. Decoupling guidelines are described in the appropriate platform design guidelines.

# <span id="page-16-1"></span>**2 .4 Front Side Bus Clock ( BCLK[ 1 :0 ] ) and Processor Clocking**

BCLK[ 1: 0] directly controls the FSB interface speed as well as the core frequency of the processor. As in previous processor generations, the processor core frequency is a multiple of the BCLK[1:0] frequency. The processor bus ratio multiplier is set during manufacturing. The default setting is for the m axim um speed of the processor. I t is possible to override this setting using software (see the Conroe and Woodcrest Processor Family BIOS Writer's Guide). This permits operation at lower frequencies than the processor's tested frequency.

The processor core frequency is configured during reset by using values stored internally during m anufacturing. The stored value sets the highest bus fraction at which the particular processor can operate. If lower speeds are desired, the appropriate ratio can be configured via the CLOCK\_FLEX\_MAX Model Specific Register (MSR). For details of operation at core frequencies lower than the m aximum rated processor speed, refer to the Intel® 64 and IA-32 Architectures Software Developer's Manual.

Clock m ultiplying within the processor is provided by the internal phase locked loop (PLL), which requires a constant frequency BCLK[ 1: 0] input, with exceptions for spread spectrum clocking. Processor DC specifications for the BCLK[ 1: 0] inputs are provided in [Table 2-21.](#page-41-1) These specifications must be met while also meeting signal integrity requirem ents as outlined in [Table 2-21.](#page-41-1) The processor utilizes differential clocks.





### <span id="page-17-1"></span>Table 2-1. Core Frequency to FSB Multiplier Configuration

#### **Notes:**

1. Individual processors operate only at or below the frequency marked on the package.<br>2. Listed frequencies are not necessarily committed production frequencies.

2. Listed frequencies are not necessarily committed production frequencies.<br>3. For valid processor core frequencies refer to the *Quad-Core Intel® Xeoni* 

3. For valid processor core frequencies, refer to the Quad-Core I ntel® Xeon® Processor 5300 Series

Specification Update. 4. The lowest bus ratio supported is 1/6.

# <span id="page-17-0"></span>**2 .4 .1 Front Side Bus Frequency Select Signals ( BSEL[ 2 :0 ] )**

Upon power up, the FSB frequency is set to the maximum supported by the individual processor. BSEL[2:0] are CMOS outputs which must be pulled up to  $V_{TT}$ , and are used to select the FSB frequency. Please refer to [Table 2-17](#page-39-1) for DC specifications. [Table 2-2](#page-17-2) defines the possible com binations of the signals and the frequency associated with each combination. The frequency is determined by the processor(s), chipset, and clock synthesizer. All FSB agents must operate at the same core and FSB frequency. See the appropriate platform design guidelines for further details.

# **BSEL2** BSEL1 BSEL0 BUS Clock Frequency 0 0 0 0 266.666 MHz 0 | 0 | 1 | Reserved 0 1 0 Reserved 0 1 1 1 1 1 Reserved 1 0 0 0 0 333.333 MHz 1 0 1 Reserved 1 1 0 Reserved 1 | 1 | 1 | Reserved

#### <span id="page-17-2"></span>Table 2-2. BSEL[2:0] Frequency Table



# <span id="page-18-0"></span>**2 .4 .2 PLL Pow er Supply**

An on-die PLL filter solution is implemented on the processor. The  $V_{CCPLL}$  input is used to provide power to the on chip PLL of the processor. Please refer to [Table 2-12](#page-26-2) for DC specifications. Refer to the appropriate platform design guidelines for decoupling and routing guidelines.

# <span id="page-18-1"></span>**2 .5 Voltage I dentification ( VI D)**

The Voltage I dentification (VID) specification for the processor is defined by the Voltage Regulator Module (VRM) and Enterprise Voltage Regulator-Down (EVRD) 11.0 Design Guidelines. The voltage set by the VID signals is the reference VR output voltage to be delivered to the processor Vcc pins. Please refer to [Table 2-18](#page-39-2) for the DC specifications for these signals. A voltage range is provided in [Table 2-12](#page-26-2) and changes with frequency. The specifications have been set such that one voltage regulator can operate with all supported frequencies.

Individual processor VID values may be calibrated during manufacturing such that two devices at the same core frequency may have different default VID settings. This is reflected by the VID range values provided in [Table 2-3.](#page-19-0)

The Quad-Core Intel® Xeon® Processor 5300 Series uses six voltage identification signals, VID[6:1], to support automatic selection of power supply voltages. [Table 2-3](#page-19-0) specifies the voltage level corresponding to the state of VID[6:1]. A '1' in this table refers to a high voltage level and a '0' refers to a low voltage level. The definition provided in [Table 2-3](#page-19-0) is not related in any way to previous I ntel® Xeon® processors or voltage regulator designs. If the processor socket is empty  $(VID[6:1] = 111111)$ , or the voltage regulation circuit cannot supply the voltage that is requested, the voltage regulator must disable itself. See the Voltage Regulator Module (VRM) and Enterprise Voltage Regulator-Down (EVRD) 11.0 Design Guidelines for further details.

Although the Voltage Regulator Module (VRM) and Enterprise Voltage Regulator-Down (EVRD) 11.0 Design Guidelines defines VI D[ 7: 0] , VI D[ 7] and VI D[ 0] are not used on the Quad-Core Intel® Xeon® Processor 5300 Series. Please refer to the Quad-Core I ntel® Xeon® Processor E5300 Series, Harpertown and Wolfdale-DP Processors Compatibility Design Guide for details.

The Quad-Core Intel® Xeon® Processor 5300 Series provide the ability to operate while transitioning to an adjacent VID and its associated processor core voltage  $(V_{CC})$ . This will represent a DC shift in the load line. It should be noted that a low-to-high or high-to-low voltage state change may result in as many VID transitions as necessary to reach the target core voltage. Transitions above the specified VID are not permitted. [Table 2-12](#page-26-2) includes VID step sizes and DC shift ranges. Minimum and maximum voltages must be maintained as shown in [Table 2-13.](#page-31-1)

The VRM or EVRD utilized must be capable of regulating its output to the value defined by the new VID. DC specifications for dynamic VID transitions are included in [Table 2-12.](#page-26-2) Refer to the Voltage Regulator Module (VRM) and Enterprise Voltage Regulator-Down (EVRD) 11.0 Design Guidelines for further details.

Power source characteristics must be quaranteed to be stable whenever the supply to the voltage regulator is stable.





# <span id="page-19-0"></span>**Table 2 - 3 . Voltage I dentification Definition**

#### **Notes:**

1. When the "111111" VID pattern is observed, the voltage regulator output should be disabled.<br>2. Shading denotes the expected VID range of the Quad-Core Intel® Xeon® Processor 5300 Series.

3. The VID range includes VID transitions that may be initiated by thermal events, assertion of the FORCEPR# signal (see [Section 6.3.3\)](#page-96-1), Extended HALT state transitions (see [Section 7.2.2\)](#page-103-2), or Enhanced Intel SpeedStep® Technology transitions<br>(see [Section 7.3](#page-106-2)). **The Extended HALT state must be enabled for the processor to remain within its sp** 4. Once the VRM/EVRD is operating after power-up, if either the Output Enable signal is de-asserted or a specific VID off code is

received, the VRM/EVRD must turn off its output (the output should go to high impedance) within 500 ms and latch off until power is cycled. Refer to Voltage Regulator Module (VRM) and Enterprise Voltage Regulator-Down (EVRD) 11.0 Design Guidelines.



#### <span id="page-20-1"></span>Table 2-4. Loadline Selection Truth Table for LL 1D[1:0]

**Note:** The LL\_ID[1:0] signals are used by the platform to select the correct loadline slope for the processor.

#### <span id="page-20-2"></span>Table 2-5. Market Segment Selection Truth Table for MS\_ID[1:0]



Note: The MS\_ID[1:0] signals are provided to indicate the Market Segment for the processor and may be used for future processor com patibility or for keying.

# <span id="page-20-0"></span>**2 .6 Reserved, Unused, or Test Signals**

All Reserved signals must remain unconnected. Connection of these signals to  $V_{CC}$ ,  $V_{TT}$  $V_{SS}$ , or to any other signal (including each other) can result in component malfunction or incom patibility with future processors. See [Section 4](#page-54-4) for a land listing of the processor and the location of all Reserved signals.

For reliable operation, always connect unused inputs or bidirectional signals to an appropriate signal level. Unused active high inputs, should be connected through a resistor to ground  $(V_{SS})$ . Unused outputs can be left unconnected; however, this may interfere with some TAP functions, com plicate debug probing, and prevent boundary scan testing. A resistor must be used when tying bidirectional signals to power or ground. When tying any signal to power or ground, a resistor will also allow for system testability. Resistor values should be within  $\pm$  20% of the impedance of the baseboard trace for FSB signals, unless otherwise noticed in the appropriate platform design guidelines. For unused  $AGTL+$  input or  $I/O$  signals, use pull-up resistors of the same value as the on-die termination resistors  $(R_{TT})$ . For details see [Table 2-20.](#page-41-0)

Some TAP, CMOS inputs and outputs do not include on-die termination. I nputs and utilized outputs m ust be term inated on the baseboard. Unused outputs m ay be term inated on the baseboard or left unconnected. Note that leaving unused outputs unterm inated m ay interfere with some TAP functions, complicate debug probing, and prevent boundary scan testing. Signal termination for these signal types is discussed in the appropriate platform design guidelines.

For each processor socket, connect the TESTIN1 and TESTIN2 signals together, then terminate the net with a 51  $\Omega$  resistor to  $V_{TT}$ .

Each of the TESTHI signals must be tied to the processor  $V_{TT}$  individually using a matched resistor, where a matched resistor has a resistance value within  $\pm$  20% of the impedance of the board transmission line traces. For example, if the trace impedance is 50  $\Omega$  then a value between 40  $\Omega$  and 60  $\Omega$  is required.



# <span id="page-21-0"></span>**2 .7 Front Side Bus Signal Groups**

The FSB signals have been combined into groups by buffer type. AGTL+ input signals have differential input buffers, which use GTLREF\_DATA\_MID, GTLREF\_DATA\_END, GTLREF\_ADD\_MID, and GTLREF\_ADD\_END as reference levels. In this document, the term "AGTL+ Input" refers to the AGTL+ input group as well as the AGTL+ I/O group when receiving. Similarly, "AGTL+ Output" refers to the AGTL+ output group as well as the  $AGTL+ I/O$  group when driving.  $AGTL+$  outputs can become active anytime and include an active PMOS pull-up transistor to assist during the first clock of a low-to-high voltage transition.

With the implementation of a source synchronous data bus comes the need to specify two sets of timing parameters. One set is for common clock signals whose timings are specified with respect to rising edge of BCLK0 (ADS#, HIT#, HITM#, etc.) and the second set is for the source synchronous signals which are relative to their respective strobe lines (data and address) as well as rising edge of BCLK0. Asynchronous signals are still present (A20M#, IGNNE#, etc.) and can become active at any time during the clock cycle. [Table 2-6](#page-21-1) identifies which signals are common clock, source synchronous and asynchronous.

## <span id="page-21-1"></span>Table 2-6. FSB Signal Groups (Sheet 1 of 2)





#### Table 2-6. FSB Signal Groups (Sheet 2 of 2)



#### **Notes:**

1. Refer to [Section 5](#page-76-3) for signal descriptions.<br>2. These signals may be driven simultaneous

- 2. These signals may be driven simultaneously by multiple agents (Wired-OR).<br>2. Not all Quad-Core Intel® Xeon® Processor 5300 Series support the addition
- 3. Not all Quad-Core I ntel® Xeon® Processor 5300 Series support the additional signals A[ 37: 36] # . Processors that support these signals will be outlined in the Quad-Core Intel® Xeon® Processor 5300 Series NDA Specification Update.

[Table 2-7](#page-22-0) and [Table 2-8](#page-22-1) outline the signals which include on-die termination  $(R_{TT})$ . [Table 2-7](#page-22-0) denotes AGTL+ signals, while [Table 2-8](#page-22-1) outlines non AGTL+ signals including open drain signals. [Table 2-9](#page-22-2) provides signal reference voltages.

#### <span id="page-22-0"></span>Table 2-7. AGTL+ Signal Description Table



#### **Note:**

1. Not all Quad-Core Intel® Xeon® Processor 5300 Series support the additional signals A[37:36]#. Processors that support these signals will be outlined in the Quad-Core Intel® Xeon® Processor 5300 Series NDA Specification Update.

#### <span id="page-22-1"></span>Table 2-8. Non AGTL+ Signal Description Table



**Note:**<br>1. Signals that have a 50 Ωpullup to V<sub>TT</sub> on package.

#### <span id="page-22-2"></span>**Table 2-9.** Signal Reference Voltages





**Note:**

1. Not all Quad-Core I ntel® Xeon® Processor 5300 Series support the additional signals A[ 37: 36] # . Processors that support these signals will be outlined in the Quad-Core Intel® Xeon® Processor 5300 Series NDA Specification Update.

# <span id="page-23-0"></span>**2 .8 CMOS Asynchronous and Open Drain Asynchronous Signals**

Legacy input signals such as A20M#, IGNNE#, INIT#, SMI#, and STPCLK# utilize CMOS input buffers. Legacy output signals such as  $FERR# / PBE#$ ,  $IERR#$ ,  $PROCHOT#$ , and THERMTRIP# utilize open drain output buffers. All of the CMOS and Open Drain signals are required to be asserted/ deasserted for at least eight BCLKs in order for the processor to recognize the proper signal state. See [Section 2.13](#page-26-0) for the DC specifications. See [Section 7](#page-102-4) for additional timing requirements for entering and leaving the low power states.

# <span id="page-23-1"></span>**2 .9 Test Access Port ( TAP) Connection**

Due to the voltage levels supported by other com ponents in the Test Access Port (TAP) logic, it is recommended that the processor(s) be first in the TAP chain and followed by any other com ponents within the system . A translation buffer should be used to connect to the rest of the chain unless one of the other com ponents is capable of accepting an input of the appropriate voltage. Similar considerations must be made for TCK, TDO, TMS, and TRST# . Two copies of each signal m ay be required with each driving a different voltage level.

# <span id="page-23-2"></span>**2 .1 0 Platform Environm ental Control I nterface ( PECI ) DC Specifications**

PECI is an Intel proprietary one-wire interface that provides a communication channel between I ntel processor and external therm al m onitoring devices. The Quad-Core I ntel® Xeon® Processor 5300 Series contains Digital Therm al Sensors (DTS) distributed throughout the die. These sensors are implem ented as analog-to-digital converters calibrated at the factor for reasonable accuracy to provide a digital representation of relative processor tem perature. PECI provides an interface to relay the highest DTS temperature within a die to external management devices for thermal/ fan speed control. More detailed information may be found in the Platform Environment Control Interface (PECI) External Architecture Specification.

# <span id="page-23-3"></span>**2 .1 0 .1 DC Characteristics**

A PECI device interface operates at a nominal voltage set by  $V_{TT}$ . The set of DC electrical specifications shown in [Table 2-10](#page-23-4) is used with devices norm ally operating from a  $V_{TT}$  interface supply.  $V_{TT}$  nominal levels will vary between processor families. All PECI devices will operate at the  $V_{TT}$  level determined by the processor installed in the system. For  $V_{TT}$  specifications, refer to [Table 2-12](#page-26-2).

<span id="page-23-4"></span>





### Table 2-10. PECI DC Electrical Limits (Sheet 2 of 2)

#### **Note:**

1. V<sub>TT</sub> supplies the PECI interface. PECI behavior does not affect V<sub>TT</sub> min/max specifications.<br>2. The leakage specification applies to powered devices on the PECI bus.

3. One node is counted for each client and one node for the system host. Extended trace lengths m ight appear as additional nodes.

## <span id="page-24-0"></span>**2 .1 0 .2 I nput Device Hysteresis**

The input buffers in both client and host models must use a Schmitt-triggered input design for improved noise immunity. Use [Figure 2-1](#page-24-2) as a guide for input buffer design.

#### <span id="page-24-2"></span>**Figure 2-1. Input Device Hysteresis**



# <span id="page-24-1"></span>**2 .1 1 Mixing Processors**

Intel supports and validates dual processor configurations only in which both processors operate with the same FSB frequency, core frequency, number of cores, and have the same internal cache sizes. Mixing components operating at different internal clock frequencies is not supported and will not be validated by Intel. Combining processors from different power segm ents is also not supported.



**Note:** Processors within a system must operate at the same frequency per bits [12:8] of the CLOCK\_FLEX\_MAX MSR; however this does not apply to frequency transitions initiated due to thermal events, Extended HALT, Enhanced Intel SpeedStep® Technology transitions, or assertion of the FORCEPR# signal.

> Not all operating systems can support dual processors with m ixed frequencies. Mixing processors of different steppings but the same model (as per CPUID instruction) is supported. Details regarding the CPUID instruction are provided in the  $AP-485$  Intel® Processor I dentification and the CPUID Instruction application note.

# <span id="page-25-0"></span>**2 .1 2 Absolute Maxim um and Minim um Ratings**

[Table 2-11](#page-25-1) specifies absolute maximum and minimum ratings only, which lie outside the functional lim its of the processor. Only within specified operation lim its, can functionality and long-term reliability be expected.

At conditions outside functional operation condition lim its, but within absolute maximum and minimum ratings, neither functionality nor long-term reliability can be expected. If a device is returned to conditions within functional operation limits after having been subjected to conditions outside these lim its, but within the absolute maximum and minimum ratings, the device may be functional, but with its lifetime degraded depending on exposure to conditions exceeding the functional operation condition lim its.

At conditions exceeding absolute maximum and minimum ratings, neither functionality nor long-term reliability can be expected. Moreover, if a device is subjected to these conditions for any length of time then, when returned to conditions within the functional operating condition lim its, it will either not function or its reliability will be severely degraded.

Although the processor contains protective circuitry to resist dam age from static electric discharge, precautions should always be taken to avoid high static voltages or electric fields.



### <span id="page-25-1"></span>**Table 2 - 1 1 . Processor Absolute Maxim um Ratings**

#### **Notes:**

1. For functional operation, all processor electrical, signal quality, mechanical and thermal specifications must be satisfied.

- Overshoot and undershoot voltage guidelines for input, output, and I/O signals are outlined in Section 3. Excessive overshoot or undershoot on any signal will likely result in perm anent dam age to the processor.
- 3. Storage temperature is applicable to storage conditions only. In this scenario, the processor must not receive a clock, and no lands can be connected to a voltage bias. Storage within these lim its will not affect the long-term reliability of the device. For functional operation, please refer to the processor case tem perature specifications.
- 4. This rating applies to the processor and does not include any tray or packaging.
- 5. Failure to adhere to this specification can affect the long-term reliability of the processor.

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# <span id="page-26-0"></span>**2 .1 3 Processor DC Specifications**

**The processor DC specifications in this section are defined at the processor die ( pads) unless noted otherw ise.** See [Table 4-1](#page-54-5) for the Quad-Core I ntel® Xeon® Processor 5300 Series land listings and [Table 5-1](#page-76-4) for signal definitions. Voltage and current specifications are detailed in [Table 2-12](#page-26-2). For platform planning refer to [Table 2-13,](#page-31-1) which provides  $V_{CC}$  Static and Transient Tolerances. This same information is presented graphically in [Figure 2-7,](#page-32-0) [Figure 2-8](#page-33-0) and [Figure 2-9.](#page-34-0)

The FSB clock signal group is detailed in [Table 2-21](#page-41-1). The DC specifications for the AGTL+ signals are listed in [Table 2-16](#page-38-1). Legacy signals and Test Access Port (TAP) signals follow DC specifications sim ilar to GTL+ . The DC specifications for the PWRGOOD input and TAP signal group are listed in [Table 2-17](#page-39-1).

[Table 2-12](#page-26-2) through [Table 2-18](#page-39-2) list the DC specifications for the processor and are valid only while meeting specifications for case temperature  $(T_{CASE}$  as specified in [Section 6\)](#page-84-3), clock frequency, and input voltages. Care should be taken to read all notes associated with each param eter.

## <span id="page-26-1"></span>**2 .1 3 .1 Flexible Motherboard Guidelines ( FMB)**

<span id="page-26-4"></span>The Flexible Motherboard (FMB) guidelines are estim ates of the m axim um values the Quad-Core Intel® Xeon® Processor 5300 Series will have over certain time periods. The values are only estimates and actual specifications for future processors m ay differ. Processors m ay or m ay not have specifications equal to the FMB value in the foreseeable future. System designers should m eet the FMB values to ensure their systems will be compatible with future processors.

<span id="page-26-3"></span>

## <span id="page-26-2"></span>Table 2-12. Voltage and Current Specifications (Sheet 1 of 3)





# Table 2-12. Voltage and Current Specifications (Sheet 2 of 3)





#### **Table 2 - 1 2 . Voltage and Current Specifications ( Sheet 3 of 3 )**

#### **Notes:**

1. Unless otherwise noted, all specifications in this table are based on final silicon characterization data.

- These voltages are targets only. A variable voltage source should exist on systems in the event that a different voltage is required. See [Section 2.5](#page-18-1) for more information.
- 3. The voltage specification requirements are measured across the VCC\_DIE\_SENSE and VSS\_DIE\_SENSE lands and across the VCC\_DIE\_SENSE2 and VSS\_DIE\_SENSE2 lands with an oscilloscope set to 100 MHz<br>bandwidth, 1.5 pF maximum probe capacitance, and 1 MΩminimum impedance. The maximum length of ground wire on the probe should be less than 5 mm. Ensure external noise from the system is not coupled in the scope probe.
- 4. The processor must not be subjected to any static V<sub>CC</sub> level that exceeds the V<sub>CC\_MAX</sub> associated with any particular current. Failure to adhere to this specification can shorten processor lifetim e.
- 5. I<sub>CC\_MAX</sub> specification is based on maximum V<sub>CC</sub> loadline Refer to [Figure 2-12](#page-40-2) for details. The processor is<br>capable of drawing I<sub>CC\_MAX</sub> for up to 10 ms. Refer to [Figure 2-5,](#page-30-1) [Figure 2-2](#page-29-0), and [Figure 2-3](#page-29-1) for further details on the average processor current draw over various time durations.
- 6. FMB is the flexible m otherboard guideline. These guidelines are for estim ation purposes only. See [Section 2.13.1](#page-26-1) for further details on FMB guidelines.
- 7. This specification represents the total current for GTLREF\_DATA\_MI D, GTLREF\_DATA\_END, GTLREF\_ADD\_MI D, and GTLREF\_ADD\_END.
- 8. V<sub>TT</sub> must be provided via a separate voltage source and must not be connected to V<sub>CC</sub>. This specification is
- measured at the land.<br>9. Minimum V<sub>CC</sub> and maximum I<sub>CC</sub> are specified at the maximum processor case temperature (T<sub>CASE</sub>) shown<br>in [Figure 6-1](#page-87-2).
- 10. This specification refers to the total reduction of the load line due to VID transitions below the specified VI D.
- 11. Individual processor VID values may be calibrated during manufacturing such that two devices at the same frequency may have different VID settings.
- 12. This specification applies to the VCCPLL land.
- 13. Baseboard bandwidth is lim ited to 20 MHz.
- 14.  $I_{\rm CC, TDC}$  is the sustained (DC equivalent) current that the processor is capable of drawing indefinitely and<br>should be used for the voltage regulator temperature assessment. The voltage regulator is responsible for m onitoring its tem perature and asserting the necessary signal to inform the processor of a therm al excursion. Please see the applicable design guidelines for further details. The processor is capable of<br>drawing I<sub>CC\_TDC</sub> indefinitely. Refer to [Figure 2-2](#page-29-0), [Figure 2-3,](#page-29-1) and [Figure 2-5,](#page-30-1)for further details on the<br>average pro characterization and is not tested.
- 15. This is the maximum total current drawn from the  $V_{TT}$  plane by only one processor with  $R_{TT}$  enabled. This specification does not include the current coming from on-board termination  $(R_{TT})$ , through the signal line.



Refer to the appropriate platform design guide and the Voltage Regulator Design Guidelines to determ ine the total  $I_{TT}$  drawn by the system. This parameter is based on design characterization and is not tested.

16. I<sub>cc\_vtt\_out</sub> is specified at 1.2 V.<br>17. I<sub>CC\_RESET</sub> is specified while PWRGOOD and RESET# are asserted. Refer to Table 2-26 for the PWRGOOD to<br>RESET# de-assertion time specification and Table 2-23 for the RESET# Pulse

#### <span id="page-29-0"></span>**Figure 2 - 2 . Quad- Core I ntel® Xeon® Processor E5 3 0 0 Series Load Current versus Tim e**



# **Notes:**

Processor or voltage regulator thermal protection circuitry should not trip for load currents greater than <sup>1</sup>cc\_tpc<sup>.</sup> the formulation. Inc. The formulation.<br>2. Not 100% tested. Specified by design characterization.

#### <span id="page-29-1"></span>**Figure 2 - 3 . Quad- Core I ntel® Xeon® Processor X5 3 0 0 Series and Load Current versus Tim e**



**Notes:**

- Processor or voltage regulator thermal protection circuitry should not trip for load currents greater than
- <sup>1</sup>cc\_tpc.<br>2. Not 100% tested. Specified by design characterization.



<span id="page-30-0"></span>



**Notes:** 1. Processor or voltage regulator therm al protection circuitry should not trip for load currents greater than

<sup>1</sup>cc\_tpc.<br>2. Not 100% tested. Specified by design characterization.

<span id="page-30-1"></span>



**Notes:**

1. Processor or voltage regulator therm al protection circuitry should not trip for load currents greater than I<sub>CC\_TDC</sub>.



2. Not 100% tested. Specified by design characterization.

<span id="page-31-0"></span>**Figure 2 - 6 . Quad- Core I ntel® Xeon® Processor L5 3 1 8 Load Current versus Tim e**



# **Notes:**

<sub>ex</sub>.<br>Processor or voltage regulator thermal protection circuitry should not trip for load currents greater than

<sup>1</sup>cc\_tpc<sup>.</sup> the formulation. Inc. The formulation.<br>2. Not 100% tested. Specified by design characterization.

#### <span id="page-31-1"></span>**Table 2 - 1 3 . VCC Static and Transient Tolerance for Quad- Core I ntel® Xeon® Processor E5 3 0 0 Series, Quad- Core I ntel® Xeon® Processor X5 3 0 0 Series, Quad- Core I ntel® Xeon® Processor L5 3 0 0 Series ( Sheet 1 of 2 )**





#### **Table 2 - 1 3 . VCC Static and Transient Tolerance for Quad- Core I ntel® Xeon® Processor E5 3 0 0 Series, Quad- Core I ntel® Xeon® Processor X5 3 0 0 Series, Quad- Core I ntel® Xeon® Processor L5 3 0 0 Series ( Sheet 2 of 2 )**



**Notes:**

1. The V<sub>CC\_MIN</sub> and V<sub>CC\_MAX</sub> loadlines represent static and transient limits. Please see [Section 2.13.2](#page-39-0) for V<sub>CC</sub> overshoot specifications.

2. This table is intended to aid in reading discrete points on [Figure 2-7](#page-32-0) for Quad-Core I ntel® Xeon® Processor E5300 , [Figure 2-8](#page-33-0) for Quad-Core I ntel® Xeon® Processor X5300 Series and [Figure 2-9](#page-34-0) for Quad-Core Intel® Xeon® Processor L5300 Series.

3. The loadlines specify voltage limits at the die measured at the VCC\_DIE\_SENSE and VSS\_DIE\_SENSE lands and across the VCC\_DIE\_SENSE2 and VSS\_DIE\_SENSE2 lands. Voltage regulation feedback for<br>voltage regulator circuits must also be taken from processor VCC\_DIE\_SENSE and VSS\_DIE\_SENSE lands and VCC\_DIE\_SENSE2 and VSS\_DIE\_SENSE2 lands. Refer to the Voltage Regulator Module (VRM) and Enterprise Voltage Regulator Down (EVRD) 11.0 Design Guidelines for socket load line guidelines and VR im plem entation. Please refer to the appropriate platform design guide for details on VR im plem entation.

4. Icc values greater than 90 A and 60 A are not applicable for the Quad-Core Intel® Xeon® Processor E5300 and Quad-Core Intel® Xeon® Processor L5300 Series, respectively.

#### <span id="page-32-0"></span>**Figure 2-7.** Quad-Core Intel® Xeon® Processor E5300 Series V<sub>CC</sub> Static and  **Transient Tolerance Load Lines**



# **Notes:**

1. The V<sub>CC\_MIN</sub> and V<sub>CC\_MAX</sub> loadlines represent static and transient limits. Please see [Section 2.13.2](#page-39-0) for VCC<br>overshoot specifications.

2. Refer to [Table 2-12](#page-26-2) for processor VID information.<br>3. Refer to [Table 2-13](#page-31-1) for V<sub>CC</sub>Static and Transient Tolerance



4. The load lines specify voltage limits at the die measured at the VCC\_DIE\_SENSE and VSS\_DIE\_SENSE lands and the VCC\_DIE\_SENSE2 and VSS\_DIE\_SENSE2 lands. Voltage regulation feedback for voltage regulator circuits must also be taken from processor VCC\_DIE\_SENSE and VSS\_DIE\_SENSE lands and VCC\_DIE\_SENSE2 and VSS\_DIE\_SENSE2 lands. Refer to the Voltage Regulator Module (VRM) and Enterprise Voltage Regulator Down (EVRD) 11.0 Design Guidelines for socket load line guidelines and VR im plem entation. Please refer to the appropriate platform design guide for details on VR im plem entation.

#### <span id="page-33-0"></span>**Figure 2 - 8 . Quad- Core I ntel® Xeon® Processor X5 3 0 0 Series VCC Static and Transient Tolerance Load Lines**



#### **Notes:**

- 1. The V<sub>CC\_MIN</sub> and V<sub>CC\_MAX</sub> loadlines represent static and transient limits. Please see [Section 2.13.2](#page-39-0) for VCC overshoot specifications.
- 
- 2. Refer to [Table 2-12](#page-26-2) for processor VID information.<br>3. Refer to [Table 2-13](#page-31-1) for V<sub>CC</sub>Static and Transient Tolerance
- 4. The load lines specify voltage limits at the die measured at the VCC\_DIE\_SENSE and VSS\_DIE\_SENSE lands and the VCC\_DIE\_SENSE2 and VSS\_DIE\_SENSE2 lands. Voltage regulation feedback for voltage<br>regulator circuits must also be taken from processor VCC\_DIE\_SENSE and VSS\_DIE\_SENSE lands and VCC\_DI E\_SENSE2 and VSS\_DI E\_SENSE2 lands. Refer to the Voltage Regulator Module (VRM) and Enterprise Voltage Regulator Down (EVRD) 11.0 Design Guidelines for socket load line guidelines and VR im plem entation. Please refer to the appropriate platform design guide for details on VR im plem entation.





#### <span id="page-34-0"></span>**Figure 2 - 9 . Quad- Core I ntel® Xeon® Processor L5 3 0 0 Series VCC Static and Transient Tolerance Load Lines**

#### **Notes:**

- 1. The V<sub>CC\_MIN</sub> and V<sub>CC\_MAX</sub> loadlines represent static and transient limits. Please see [Section 2.13.2](#page-39-0) for VCC<br>overshoot specifications.
- 2. Refer to [Table 2-12](#page-26-2) for processor VID information.<br>3. Refer to Table 2-13 for  $V_{CC}$ Static and Transient Tol
- 3. Refer to [Table 2-13](#page-31-1) for  $V_{CC}$ Static and Transient Tolerance.<br>4. The load lines specify voltage limits at the die measured a
- The load lines specify voltage limits at the die measured at the VCC\_DIE\_SENSE and VSS\_DIE\_SENSE lands and the VCC\_DIE\_SENSE2 and VSS\_DIE\_SENSE2 lands. Voltage regulation feedback for voltage regulator circuits must also be taken from processor VCC\_DIE\_SENSE and VSS\_DIE\_SENSE lands and<br>VCC\_DIE\_SENSE2 and VSS\_DIE\_SENSE2 lands. Refer to the *Voltage Regulator Module (VRM) and* Enterprise Voltage Regulator Down (EVRD) 11.0 Design Guidelines for socket load line guidelines and VR im plem entation. Please refer to the appropriate platform design guide for details on VR im plem entation

### <span id="page-34-1"></span>**Table 2 - 1 4 . VCC Static and Transient Tolerance for Quad- Core I ntel® Xeon® Processor X5 3 6 5 Series ( Sheet 1 of 2 )**



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#### **Table 2 - 1 4 . VCC Static and Transient Tolerance for Quad- Core I ntel® Xeon® Processor X5 3 6 5 Series ( Sheet 2 of 2 )**

#### **Notes:**

1. The V<sub>CC\_MIN</sub> and V<sub>CC\_MAX</sub> loadlines represent static and transient limits. Please see [Section 2.13.2](#page-39-0) for V<sub>CC</sub><br>overshoot specifications.

2. This table is intended to aid in reading discrete points on [Figure 2-10](#page-36-0) for Quad-Core Intel® Xeon® Processor X5365 Series

3. The loadlines specify voltage limits at the die measured at the VCC\_DIE\_SENSE and VSS\_DIE\_SENSE lands and across the VCC\_DI E\_SENSE2 and VSS\_DI E\_SENSE2 lands. Voltage regulation feedback for voltage regulator circuits must also be taken from processor VCC\_DIE\_SENSE and VSS\_DIE\_SENSE lands and<br>VCC\_DIE\_SENSE2 and VSS\_DIE\_SENSE2 lands. Refer to the Voltage Regulator Module (VRM) and Enterprise Voltage Regulator Down (EVRD) 11.0 Design Guidelines for socket load line guidelines and VR im plem entation. Please refer to the appropriate platform design guide for details on VR im plem entation.




#### T **Figure 2 - 1 0 . Quad- Core I ntel® Xeon® Processor X5 3 6 5 Series VCC Static and Transient Tolerance Load Lines**

- **Notes:** 1. The V<sub>CC\_MIN</sub> and V<sub>CC\_MAX</sub> loadlines represent static and transient limits. Please see [Section 2.13.2](#page-39-0) for VCC<br>overshoot specifications.
- 
- 2. Refer to [Table 2-12](#page-26-0) for processor VID information.<br>3. Refer to [Table 2-14](#page-34-0) for V<sub>CC</sub>Static and Transient Tolerance.
- 4. The load lines specify voltage limits at the die measured at the VCC\_DIE\_SENSE and VSS\_DIE\_SENSE lands and the VCC\_DIE\_SENSE2 and VSS\_DIE\_SENSE2 lands. Voltage regulation feedback for voltage<br>regulator circuits must also be taken from processor VCC\_DIE\_SENSE and VSS\_DIE\_SENSE lands and VCC\_DIE\_SENSE2 and VSS\_DIE\_SENSE2 lands. Refer to the Voltage Regulator Module (VRM) and Enterprise Voltage Regulator Down (EVRD) 11.0 Design Guidelines for socket load line guidelines and VR im plem entation. Please refer to the appropriate platform design guide for details on VR im plem entation



## <span id="page-37-0"></span>**Table 2 - 1 5 . VCC Static and Transient Tolerance for Quad- Core I ntel® Xeon® Processor L5 3 1 8 Series**



#### **Notes:**

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1. The V<sub>CC\_MIN</sub> and V<sub>CC\_MAX</sub> loadlines represent static and transient limits. Please see [Section 2.13.2](#page-39-0) for V<sub>CC</sub><br>overshoot specifications.

2. This table is intended to aid in reading discrete points on [Figure 2-11](#page-38-0) for Quad-Core Intel® Xeon® Processor L5318

3. The loadlines specify voltage limits at the die measured at the VCC\_DIE\_SENSE and VSS\_DIE\_SENSE lands and across the VCC\_DI E\_SENSE2 and VSS\_DI E\_SENSE2 lands. Voltage regulation feedback for voltage regulator circuits must also be taken from processor VCC\_DIE\_SENSE and VSS\_DIE\_SENSE lands and VCC\_DIE\_SENSE2 and VSS\_DIE\_SENSE2 lands. Refer to the Voltage Regulator Module (VRM) and Enterprise Voltage Regulator Down (EVRD) 11.0 Design Guidelines for socket load line guidelines and VR im plem entation. Please refer to the appropriate platform design guide for details on VR im plem entation.





## <span id="page-38-0"></span>**Figure 2 - 1 1 . Quad- Core I ntel® Xeon® Processor L5 3 1 8 VCC Static and Transient Tolerance Load Lines**

#### **Notes:**

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- 1. The V<sub>CC\_MIN</sub> and V<sub>CC\_MAX</sub> loadlines represent static and transient limits. Please see [Section 2.13.2](#page-39-0) for VCC<br>overshoot specifications.
- 2. Refer to [Table 2-12](#page-26-0) for processor VID information.<br>3. Refer to Table 2-15 for V<sub>CC</sub>Static and Transient Tol
- 3. Refer to [Table 2-15](#page-37-0) for  $V_{CC}$ Static and Transient Tolerance.<br>4. The load lines specify voltage limits at the die measured a
- The load lines specify voltage limits at the die measured at the VCC\_DIE\_SENSE and VSS\_DIE\_SENSE lands and the VCC\_DIE\_SENSE2 and VSS\_DIE\_SENSE2 lands. Voltage regulation feedback for voltage regulator circuits must also be taken from processor VCC\_DIE\_SENSE and VSS\_DIE\_SENSE lands and VCC\_DIE\_SENSE2 and VSS\_DIE\_SENSE2 lands. Refer to the Voltage Regulator Module (VRM) and Enterprise Voltage Regulator Down (EVRD) 11.0 Design Guidelines for socket load line guidelines and VR im plem entation. Please refer to the appropriate platform design guide for details on VR im plem entation.

## **Table 2 - 1 6 . AGTL+ Signal Group Specifications**



#### **Notes:**

- 1. Unless otherwise noted, all specifications in this table apply to all processor frequencies.<br>2.  $V_{\text{II}}$  is defined as the maximum voltage level at a receiving agent that will be interpreted
- $V_{\vert L}$  is defined as the maximum voltage level at a receiving agent that will be interpreted as a logical low value.
- 3.  $V_{\text{H}}$  is defined as the minimum voltage level at a receiving agent that will be interpreted as a logical high value.
- 4. V<sub>IH</sub> and V<sub>OH</sub> may experience excursions above V<sub>TT</sub>. However, input signal drivers must comply with the signal quality specifications.
- 5. This is the pull down driver resistance. Refer to processor I/O Buffer Models for I/V characteristics.<br>Measured at 0.31\* V<sub>TT</sub>. R<sub>ON</sub> (min) = 0.225\* R<sub>TT</sub>. R<sub>ON</sub> (typ) = 0.250\* R<sub>TT</sub>. R<sub>ON</sub> (max) = 0.275\* R<sub>TT</sub>.



- 6. GTLREF should be generated from  $V_{TT}$  with a 1% tolerance resistor divider. The V<sub>TT</sub> referred to in these specifications is the instantaneous  $V_{TT}^-$ .
- 7. Specified when on-die R<sub>TT</sub> and R<sub>ON</sub> are turned off. V<sub>IN</sub> between 0 and V<sub>TT</sub>.<br>8. This is the measurement at the pin.
- 

## **Table 2 - 1 7 . CMOS Signal I nput/ Output Group and TAP Signal Group DC Specifications**



#### **Notes:**

1. Unless otherwise noted, all specifications in this table apply to all processor frequencies.<br>2. The V<sub>TT</sub> referred to in these specifications refers to instantaneous V<sub>TT</sub>.

2. The V<sub>TT</sub> referred to in these specifications refers to instantaneous V<sub>TT</sub>.<br>3. Refer to the processor I/O Buffer Models for I/V characteristics.

Refer to the processor I/O Buffer Models for I/V characteristics.

4. Measured at  $0.1^{\circ}$  V<sub>TT</sub>.<br>5. Measured at 0.9  $^{\circ}$  V<sub>TT</sub>.

5. Measured at 0.9\*V<sub>TT</sub>.<br>6. For Vin between 0 V and V<sub>TT</sub>. Measured when the driver is tristated.

7. This is the measurement at the pin.

## **Table 2 - 1 8 . Open Drain Output Signal Group DC Specifications**



#### **Notes:**

1. Unless otherwise noted, all specifications in this table apply to all processor frequencies.<br>2. Measured at  $0.2^* V_{\text{TL}}$ 

2. Measured at  $0.2^* V_{TT}$ <br>3.  $V_{OH}$  is determined by

 $V_{OH}$  is determined by value of the external pullup resistor to  $V_{TH}$ . Please refer to platform design guide for details.

4. For V<sub>IN</sub> between 0 V and V<sub>OH</sub>.<br>5. This is the measurement at the pin.

## <span id="page-39-0"></span>**2 .1 3 .2 V CC Overshoot Specification**

Processors can tolerate short transient overshoot events where  $V_{CC}$  exceeds the VID voltage when transitioning from a high-to-low current load condition. This overshoot cannot exceed VID +  $V_{OS}$  MAX ( $V_{OS}$  MAX is the maximum allowable overshoot above VID). These specifications apply to the processor die voltage as measured across the VCC\_DIE\_SENSE and VSS\_DIE\_SENSE lands and across the VCC\_DIE\_SENSE2 and VSS\_DIE\_SENSE2 lands.

## <span id="page-39-1"></span>Table 2-19. V<sub>CC</sub> Overshoot Specifications





<span id="page-40-0"></span>



#### **Notes:**

1.  $V_{OS}$  is the measured overshoot voltage.<br>2  $V_{OS}$  is the measured time duration above

 $T_{OS}$  is the measured time duration above VID.

## **2 .1 3 .3 Die Voltage Validation**

Core voltage (VCC) overshoot events at the processor must meet the specifications in [Table 2-19](#page-39-1) when measured across the VCC\_DIE\_SENSE and VSS\_DIE\_SENSE lands and across the VCC\_DIE\_SENSE2 and VSS\_DIE\_SENSE2 lands. Overshoot events that are < 10 ns in duration may be ignored. These measurements of processor die level overshoot should be taken with a 100 MHz bandwidth lim ited oscilloscope.

## **2 .1 4 AGTL+ FSB Specifications**

Routing topologies are dependent on the processors supported and the chipset used in the design. Please refer to the appropriate platform design guidelines for specific implementation details. In most cases, termination resistors are not required as these are integrated into the processor silicon. See [Table 2-7](#page-22-0) for details on which signals do not include on-die termination. Please refer to [Table 2-20](#page-41-0) for  $R_{TT}$  values.

Valid high and low levels are determined by the input buffers via comparing with a reference voltage called GTLREF\_DATA\_MID, GTLREF\_DATA\_END, GTLREF\_ADD\_MID, and GTLREF\_ADD\_END. GTLREF\_DATA\_MI D and GTLREF\_DATA\_END are the reference voltage for the FSB 4X data signals, GTLREF\_ADD\_MID and GTLREF\_ADD\_END are the reference voltage for the FSB 2X address signals and common clock signals. [Table 2-20](#page-41-0) lists the GTLREF\_DATA\_MID, GTLREF\_DATA\_END, GTLREF\_ADD\_MID, and GTLREF\_ADD\_END specifications.

The AGTL+ reference voltages (GTLREF\_DATA\_MID, GTLREF\_DATA\_END, GTLREF\_ADD\_MID, and GTLREF\_ADD\_END) must be generated on the baseboard using high precision voltage divider circuits. Refer to the appropriate platform design guidelines for implementation details.



## <span id="page-41-0"></span>**Table 2 - 2 0 . AGTL+ Bus Voltage Definitions**



#### **Note:**

1. Unless otherwise noted, all specifications in this table apply to all processor frequencies.<br>2. The tolerances for this specification have been stated generically to enable system design

- 2. The tolerances for this specification have been stated generically to enable system designer to calculate the minimum values across the range of  $V_{TT}$ .
- 3. GTLREF\_DATA\_MID, GTLREF\_DATA\_END, GTLREF\_ADD\_MID, and GTLREF\_ADD\_END is generated from V<sub>TT</sub><br>on the baseboard by a voltage divider of 1% resistors. The minimum and maximum specifications account for this resistor tolerance. Refer to the appropriate platform design guidelines for im plem entation details.
- The V<sub>TT</sub> referred to in these specifications is the instantaneous V<sub>TT</sub>.<br>4. R<sub>TT</sub> is the on-die termination resistance measured at V<sub>OL</sub> of the AGTL+ output driver. Measured at  $0.31*V_{TT}$  R<sub>TT</sub> is connected to V<sub>TT</sub> on die. Refer to processor I/O Buffer Models for I/V characteristics.
- 5. COMP resistance must be provided on the system board with +/- 1% resistors. See the applicable platform design guide for im plementation details.

## **Table 2 - 2 1 . FSB Differential BCLK Specifications**



#### **Note:**

- 1. Unless otherwise noted, all specifications in this table apply to all processor frequencies. 2. Rise and fall tim es are m easured single-ended between 245 m V and 455 m V of the clock swing.
- 3. Crossing Voltage is defined as the instantaneous voltage value when the rising edge of BCLK0 is equal to the falling edge of BCLK1.
- 
- 4. V<sub>Havg</sub> is the statistical average of the V<sub>H</sub> measured by the oscilloscope.<br>5. Overshoot is defined as the absolute value of the maximum voltage.
- 6. Undershoot is defined as the absolute value of the minimum voltage.



- 7. Ringback Margin is defined as the absolute voltage difference between the maximum Rising Edge Ringback and the maximum Falling Edge Ringback.
- 8. Threshold Region is defined as a region entered around the crossing point voltage in which the differential receiver switches. It includes input threshold hysteresis.
- 9. The crossing point m ust m eet the absolute and relative crossing point specifications sim ultaneously.
- 
- 
- 10. V<sub>Havg</sub> can be measured directly using "Vtop" on Agilent and "High" on Tektronix oscilloscopes.<br>11. For V<sub>IN</sub> between 0 V and V<sub>H</sub>.<br>12. ∆V<sub>CROSS</sub> is defined as the total variation of all crossing voltages as def

**Figure 2 - 1 3 . Electrical Test Circuit**



## **Figure 2 - 1 4 . TCK Clock W aveform**





**Figure 2 - 1 5 . Differential Clock W aveform**

<span id="page-43-0"></span>

<span id="page-43-1"></span>**Figure 2 - 1 6 . Differential Clock Crosspoint Specification**



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## **3 Mechanical Specifications**

The Quad-Core I ntel® Xeon® Processor 5300 Series are packaged in a Flip Chip Land Grid Array (FC-LGA6) package that interfaces to the baseboard via a LGA771 socket. The package consists of two processor dies mounted on a pinless substrate with 771 lands. An integrated heat spreader (IHS) is attached to the package substrate and core and serves as the interface for processor com ponent therm al solutions such as a heatsink. [Figure 3-1](#page-44-0) shows a sketch of the processor package components and how they are assembled together. Refer to the LGA771 Socket Design Guidelines for complete details on the LGA771 socket.

The package components shown in [Figure 3-1](#page-44-0) include the following:

- Integrated Heat Spreader (IHS)
- Thermal Interface Material (TIM)
- Processor Die
- Package Substrate
- Landside capacitors
- Package Lands

## <span id="page-44-0"></span>**Figure 3-1. Processor Package Assembly Sketch**



**Note:** This drawing is not to scale and is for reference only.

## **3 .1 Package Mechanical Draw ings**

The package mechanical drawings are shown in [Figure 3-2](#page-45-0) through [Figure 3-4](#page-47-0). The drawings include dim ensions necessary to design a therm al solution for the processor including:

- Package reference and tolerance dim ensions (total height, length, width, and so forth)
- IHS parallelism and tilt
- Land dim ensions
- Top-side and back-side com ponent keepout dim ensions
- Reference datums

**Note:** All drawing dimensions are in mm [in.].





<span id="page-45-0"></span>Figure 3-2. Processor Package Drawing (Sheet 1 of 3)

**Note:** Guidelines on potential IHS flatness variation with socket load plate actuation and installation of the cooling solution is<br>available in the processor Thermal/Mechanical Design Guidelines.





## Figure 3-3. Processor Package Drawing (Sheet 2 of 3)





<span id="page-47-0"></span>Figure 3-4. Processor Package Drawing (Sheet 3 of 3)



## **3 .2 Processor Com ponent Keepout Zones**

The processor may contain components on the substrate that define component keepout zone requirements. A thermal and mechanical solution design m ust not intrude into the required keepout zones. Decoupling capacitors are typically mounted to either the topside or landside of the package substrate. See [Figure 3-4](#page-47-0) for keepout zones.

## **3 .3 Package Loading Specifications**

[Table 3-1](#page-48-0) provides dynamic and static load specifications for the processor package. These mechanical load limits should not be exceeded during heatsink assembly, m echanical stress testing or standard drop and shipping conditions. The heatsink attach solutions m ust not include continuous stress onto the processor with the exception of a uniform load to maintain the heatsink-to-processor thermal interface. Also, any m echanical system or com ponent testing should not exceed these lim its. The processor package substrate should not be used as a m echanical reference or loadbearing surface for therm al or m echanical solutions.

## <span id="page-48-0"></span>**Table 3-1.** Package Loading Specifications



#### **Notes:**

- 1. These specifications apply to uniform compressive loading in a direction perpendicular to the IHS top surface.
- 2. This is the minimum and maximum static force that can be applied by the heatsink and retention solution to maintain the heatsink and processor interface.
- 3. These specifications are based on lim ited testing for design characterization. Loading lim its are for the LGA771 socket.
- 4. Dynamic compressive load applies to all board thickness.<br>5. Dynamic loading is defined as an 11 ms duration average
- Dynamic loading is defined as an 11 ms duration average load superimposed on the static load requirem ent.
- 6. Test condition used a heatsink m ass of 1 lbm with 50 g acceleration m easured at heatsink m ass. The dynam ic portion of this specification in the product application can have flexibility in specific values, but the ultim ate product of m ass tim es acceleration should not exceed this dynam ic load.
- 7. Transient bend is defined as the transient board deflection during manufacturing such as board assembly and system integration. It is a relatively slow bending event compared to shock and vibration tests.
- 8. For more information on the transient bend limits, please refer to the MAS document entitled Manufacturing with Intel® Components using 771-land LGA Package that Interfaces with the Motherboard via a LGA771 Socket.
- 9. Refer to the Quad-Core Intel® Xeon® Processor 5300 Series Thermal/Mechanical Design Guidelines for inform ation on heatsink clip load m etrology.



## **3 .4 Package Handling Guidelines**

[Table 3-2](#page-49-0) includes a list of quidelines on a package handling in terms of recommended m axim um loading on the processor I HS relative to a fixed substrate. These package handling loads may be experienced during heatsink removal.

## <span id="page-49-0"></span>Table 3-2. Package Handling Guidelines



**Notes:**

1. A shear load is defined as a load applied to the IHS in a direction parallel to the IHS top surface.<br>2. A tensile load is defined as a pulling load applied to the IHS in a direction normal to the IHS surf

2. A tensile load is defined as a pulling load applied to the I HS in a direction norm al to the I HS surface. 3. A torque load is defined as a twisting load applied to the I HS in an axis of rotation norm al to the I HS top surface.

4. These guidelines are based on lim ited testing for design characterization and incidental applications (one time only).

5. Handling guidelines are for the package only and do not include the lim its of the processor socket.

## **3 .5 Package I nsertion Specifications**

The Quad-Core I ntel® Xeon® Processor 5300 Series can be inserted and removed 15 times from an LGA771 socket, which meets the criteria outlined in the LGA771 Socket Design Guidelines.

## **3 .6 Processor Mass Specifications**

The typical mass of the Quad-Core Intel® Xeon® Processor 5300 Series is 21.5 g (0.76 oz). This includes all com ponents which m ake up the entire processor product.

## **3 .7 Processor Materials**

The Quad-Core I ntel® Xeon® Processor 5300 Series are assembled from several com ponents. The basic m aterial properties are described in [Table 3-3.](#page-49-1)

## <span id="page-49-1"></span>**Table 3-3. Processor Materials**





## **3 .8 Processor Markings**

[Figure 3-5](#page-50-0) shows the topside markings on the processor. This diagram aids in the identification of the Quad-Core Intel® Xeon® Processor 5300 Series.

## <span id="page-50-0"></span>**Figure 3-5. Processor Top-side Markings (Example)**



**Notes:**

1. 2D matrix is required for engineering samples only (encoded with ATPO-S/N)

## **3 .9 Processor Land Coordinates**

[Figure 3-6](#page-51-0) and [Figure 3-7](#page-52-0) show the top and bottom view of the processor land coordinates, respectively. The coordinates are referred to throughout the docum ent to identify processor lands.





## <span id="page-51-0"></span>**Figure 3-6. Processor Land Coordinates, Top View**





<span id="page-52-0"></span>



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**Mechanical Specifications**



# **4 Land Listing**

## **4 .1 Quad- Core I ntel® Xeon® Processor 5 3 0 0 Series Pin Assignm ents**

This section provides sorted land list in [Table 4-1](#page-54-0) and [Table 4-2](#page-66-0). [Table 4-1](#page-54-0) is a listing of all processor lands ordered alphabetically by land nam e. [Table 4-2](#page-66-0) is a listing of all processor lands ordered by land number.

## **4 .1 .1 Land Listing by Land Nam e**

## <span id="page-54-0"></span>**Table 4 - 1 . Land Listing by Land Nam e ( Sheet 1 of 2 3 )**











## **Table 4 - 1 . Land Listing by Land Nam e ( Sheet 3 of 2 3 )**



## **Table 4 - 1 . Land Listing by Land Nam e ( Sheet 4 of 2 3 )**







## **Table 4 - 1 . Land Listing by Land Nam e ( Sheet 5 of 2 3 )**

## **Table 4 - 1 . Land Listing by Land Nam e ( Sheet 6 of 2 3 )**







## **Table 4 - 1 . Land Listing by Land Nam e ( Sheet 7 of 2 3 )**



## **Table 4 - 1 . Land Listing by Land Nam e ( Sheet 8 of 2 3 )**





## **Table 4 - 1 . Land Listing by Land Nam e ( Sheet 9 of 2 3 )**



## **Table 4 - 1 . Land Listing by Land Nam e ( Sheet 1 0 of 2 3 )**







## **Table 4 - 1 . Land Listing by Land Nam e ( Sheet 1 1 of 2 3 )**



### **Table 4 - 1 . Land Listing by Land Nam e ( Sheet 1 2 of 2 3 )**







**Table 4 - 1 . Land Listing by Land Nam e ( Sheet 1 3 of 2 3 )**

## **Table 4 - 1 . Land Listing by Land Nam e ( Sheet 1 4 of 2 3 )**







## **Table 4 - 1 . Land Listing by Land Nam e ( Sheet 1 5 of 2 3 )**



### **Table 4 - 1 . Land Listing by Land Nam e ( Sheet 1 6 of 2 3 )**







## **Table 4 - 1 . Land Listing by Land Nam e ( Sheet 1 7 of 2 3 )**

## **Table 4 - 1 . Land Listing by Land Nam e ( Sheet 1 8 of 2 3 )**







## **Table 4 - 1 . Land Listing by Land Nam e ( Sheet 1 9 of 2 3 )**



### **Table 4 - 1 . Land Listing by Land Nam e ( Sheet 2 0 of 2 3 )**







## **Table 4 - 1 . Land Listing by Land Nam e ( Sheet 2 1 of 2 3 )**

## **Table 4 - 1 . Land Listing by Land Nam e ( Sheet 2 2 of 2 3 )**





## **Table 4 - 1 . Land Listing by Land Nam e ( Sheet 2 3 of 2 3 )**





## **4 .1 .2 Land Listing by Land Num ber**

## <span id="page-66-0"></span>**Table 4 - 2 . Land Listing by Land Num ber ( Sheet 1 of 2 0 )**



## **Table 4 - 2 . Land Listing by Land Num ber ( Sheet 2 of 2 0 )**







## **Table 4 - 2 . Land Listing by Land Num ber ( Sheet 3 of 2 0 )**











## **Table 4 - 2 . Land Listing by Land Num ber ( Sheet 5 of 2 0 )**

## **Table 4 - 2 . Land Listing by Land Num ber ( Sheet 6 of 2 0 )**







## **Table 4 - 2 . Land Listing by Land Num ber ( Sheet 7 of 2 0 )**











## **Table 4 - 2 . Land Listing by Land Num ber ( Sheet 9 of 2 0 )**

## **Table 4 - 2 . Land Listing by Land Num ber ( Sheet 1 0 of 2 0 )**







## **Table 4 - 2 . Land Listing by Land Num ber ( Sheet 1 1 of 2 0 )**



#### **Table 4 - 2 . Land Listing by Land Num ber ( Sheet 1 2 of 2 0 )**






### **Table 4 - 2 . Land Listing by Land Num ber ( Sheet 1 3 of 2 0 )**

#### **Table 4 - 2 . Land Listing by Land Num ber ( Sheet 1 4 of 2 0 )**





### **Table 4 - 2 . Land Listing by Land Num ber ( Sheet 1 5 of 2 0 )**











### **Table 4 - 2 . Land Listing by Land Num ber ( Sheet 1 7 of 2 0 )**

#### **Table 4 - 2 . Land Listing by Land Num ber ( Sheet 1 8 of 2 0 )**







### **Table 4 - 2 . Land Listing by Land Num ber ( Sheet 1 9 of 2 0 )**



#### **Table 4 - 2 . Land Listing by Land Num ber ( Sheet 2 0 of 2 0 )**



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# **5 Signal Definitions**

# **5 .1 Signal Definitions**

### <span id="page-76-0"></span>Table 5-1. Signal Definitions (Sheet 1 of 7)





# Table 5-1. Signal Definitions (Sheet 2 of 7)







### Table 5-1. Signal Definitions (Sheet 3 of 7)





### Table 5-1. Signal Definitions (Sheet 4 of 7)









### Table 5-1. Signal Definitions (Sheet 6 of 7)







### Table 5-1. Signal Definitions (Sheet 7 of 7)

#### **Notes:**

1. For this processor land on the Quad-Core Intel® Xeon® Processor 5300 Series, the maximum number of symmetric agents is one. Maxim um num ber of priority agents is zero. 2. For this processor land on the Quad-Core I ntel® Xeon® Processor 5300 Series, the m axim um num ber of sym m etric agents is

two. Maximum number of priority agents is zero.

3. For this processor land on the Quad-Core I ntel® Xeon® Processor 5300 Series, the m axim um num ber of sym m etric agents is two. Maximum number of priority agents is one.<br>4. Not all Quad-Core Intel® Xeon® Processor 5300 Series support signals A[37:36]#. Processors that support these signals will

be outlined in the Quad-Core I ntel® Xeon® Processor 5300 Series NDA Specification Update.







# **6 Therm al Specifications**

# **6 .1 Package Therm al Specifications**

The Quad-Core I ntel® Xeon® Processor 5300 Series requires a thermal solution to maintain temperatures within its operating lim its. Any attem pt to operate the processor outside these operating limits may result in permanent damage to the processor and potentially other components within the system. As processor technology changes, thermal management becomes increasingly crucial when building com puter systems. Maintaining the proper therm al environm ent is key to reliable, long-term system operation.

A com plete solution includes both com ponent and system level therm al m anagem ent features. Com ponent level therm al solutions can include active or passive heatsinks attached to the processor integrated heat spreader (IHS). Typical system level thermal solutions may consist of system fans combined with ducting and venting.

This section provides data necessary for developing a complete thermal solution. For more information on designing a component level thermal solution, refer to the Quad-Core I ntel® Xeon® Processor 5300 Series Thermal/ Mechanical Design Guidelines and the Quad-Core Intel® Xeon® Processor LV5318 in Embedded Applications Thermal/ Mechanical Design Guidelines.

**Note:** The boxed processor will ship with a com ponent therm al solution. Refer to [Section 8](#page-108-0) for details on the boxed processor.

### **6 .1 .1 Therm al Specifications**

To allow the optim al operation and long-term reliability of I ntel processor-based systems, the processor must remain within the minimum and maximum case tem perature  $(T<sub>CASE</sub>)$  specifications as defined by the applicable thermal profile. Thermal solutions not designed to provide this level of therm al capability m ay affect the long-term reliability of the processor and system. For more details on thermal/ mechanical design guidelines.

The Quad-Core I ntel® Xeon® Processor 5300 Series implement a methodology for m anaging processor tem peratures which is intended to support acoustic noise reduction through fan speed control and to assure processor reliability. Selection of the appropriate fan speed is based on the relative temperature data reported by the processor's Platform Environment Control Interface (PECI) bus as described in [Section 6.4](#page-99-1). The temperature reported over PECI is always a negative value and represents a delta below the onset of therm al control circuit (TCC) activation, as indicated by PROCHOT# (see [Section 6.3,](#page-95-0) Processor Thermal Features). Systems that implement fan speed control must be designed to use this data. Systems that do not alter the fan speed only need to guarantee the case tem perature m eets the therm al profile specifications.

The Quad-Core Intel® Xeon® Processor E5300 (see [Figure 6-1;](#page-87-0) [Table 6-2](#page-87-1)), Quad-Core I ntel® Xeon® Processor L5300 Series (see [Figure 6-4;](#page-92-0) [Table 6-9](#page-92-1)), and Quad-Core I ntel® Xeon® Processor X5365 Series (see [Figure 6-3;](#page-90-0) [Table 6-7\)](#page-91-0) support a single Therm al Profile. For these processors, it is expected that the Therm al Control Circuit (TCC) would only be activated for very brief periods of time when running the most

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power-intensive applications. Refer to the Quad-Core Intel® Xeon® Processor 5300 Series Thermal/Mechanical Design Guidelinesfor details on system thermal solution design, therm al profiles and environm ental considerations.

For the Quad-Core I ntel® Xeon® Processor X5300 Series, I ntel has developed two therm al profiles, either of which can be implem ented. Both ensure adherence to I ntel reliability requirem ents. Therm al Profile A (see [Figure 6-2](#page-88-0); [Table 6-4](#page-89-0)) is representative of a volum etrically unconstrained therm al solution (that is, industry enabled 2U heatsink). In this scenario, it is expected that the Thermal Control Circuit (TCC) would only be activated for very brief periods of time when running the most power intensive applications. Thermal Profile B (see [Figure 6-2;](#page-88-0) [Table 6-5](#page-89-1)) is indicative of a constrained therm al environm ent (that is, 1U form factor). Because of the reduced cooling capability represented by this therm al solution, the probability of TCC activation and performance loss is increased. Additionally, utilization of a therm al solution that does not m eet Therm al Profile B will violate the therm al specifications and m ay result in permanent damage to the processor. Refer to the Quad-Core Intel® Xeon® Processor 5300 Series Thermal/ Mechanical Design Guidelines for details on system therm al solution design, thermal profiles and environmental considerations.

The upper point of the thermal profile consists of the Therm al Design Power (TDP) and the associated  $T<sub>CASE</sub>$  value. It should be noted that the upper point associated with the Quad-Core Intel® Xeon® Processor X5300 Series Thermal Profile B ( $x = TDP$  and  $y =$  $T_{CASEMAX~B}$  @ TDP) represents a thermal solution design point. In actuality the processor case tem perature will not reach this value due to TCC activation (see [Figure 6-2](#page-88-0) for Quad-Core I ntel® Xeon® Processor X5300 Series). The lower point of the thermal profile consists of  $x = P_{PROFILE\_MIN}$  and  $y = T_{CASE\_MAX}$  @ P\_PROFILE\_MIN.  $P_{PROFILE\_MIN}$  is defined as the processor power at which  $T_{CASE}$ , calculated from the therm al profile, is equal to 50° C.

Analysis indicates that real applications are unlikely to cause the processor to consum e maximum power dissipation for sustained time periods. Intel recommends that com plete therm al solution designs target the Therm al Design Power (TDP), instead of the maximum processor power consumption. The Thermal Monitor feature is intended to help protect the processor in the event that an application exceeds the TDP recommendation for a sustained time period. For more details on this feature, refer to [Section 6.3](#page-95-0). To ensure maximum flexibility for future requirements, systems should be designed to the Flexible Motherboard (FMB) guidelines, even if a processor with lower power dissipation is currently planned. **Therm al Monitor 1 and Therm al Monitor 2 feature m ust be enabled for the processor to rem ain w ithin its specifications.**

Intel has developed thermal profiles specific to enable the Dual-Core Intel® Xeon® Processor LV 5318, to be used in environments compliant with NEBS\* Level 3 ambient operating temperature requirements. At a minimum, NEBS Level 3 requires a nominal am bient operating tem perature of 40° C, with short-term excursions to 55° C. "Shortterm" is defined as a maximum of 96 hours per instance, for a total maximum of 360 hours per year, and a maximum of 15 instances per year.

To com ply with these am bient operating tem perature requirem ents, I ntel has developed a corresponding Nominal Thermal Profile and Short-Term Thermal Profile. For normal operation, the processor must remain within the minimum and maximum case temperature ( $T_{CASE}$ ) specifications as defined by the Nominal Thermal Profile. For short-term operating conditions (m axim um 96 hours per instance, m axim um 360 hours per year, m axim um of 15 instances per year), the processor m ay rem ain within the minimum and maximum  $T_{CASE}$ , as defined by the Short-Term Thermal Profile. For environments that do not require NEBS Level 3 compliance, the processor must always remain within the minimum and maximum case temperature  $(T_{CASE})$  specifications as defined by the Nominal Thermal Profile.



To provide greater flexibility in environm ental conditions and thermal solution design, the Nom inal Therm al Profile and the Short-Term Therm al Profile are each specified 5° C above the NEBS Level 3 ambient operating temperature requirements of 40° C nominal and 55° C short-term. The Nominal Thermal Profile is defined at an ambient operating tem perature of 45° C, and the Short-Term Thermal Profile is defined at an am bient operating temperature of 60° C.

Both of these therm al profiles ensure adherence to I ntel reliability requirem ents. I t is expected that the Thermal Control Circuit (TCC) would only be activated for very brief periods of time when running the most power intensive applications. Utilization of a thermal solution that exceeds the Short-Term Therm al Profile, or which operates at the Short-Term Therm al Profile for a duration longer than the specified limits will violate the thermal specifications and may result in perm anent dam age to the processor. Refer to the Quad-Core Intel® Xeon® Processor LV 5318 in Embedded Applications Thermal/ Mechanical Design Guidelines for details on system thermal solution design, thermal profiles and environmental considerations.

#### <span id="page-86-0"></span>**Table 6 - 1 . Quad- Core I ntel® Xeon® Processor E5 3 0 0 Series Therm al Specifications**



#### **Notes:**

- 1. These values are specified at  $V_{\text{CC}_{\text{MAX}}}$  for all processor frequencies. Systems must be designed to ensure the processor is not to be subjected to any static V<sub>CC</sub> and I<sub>CC</sub> combination wherein V<sub>CC</sub> exceeds V<sub>CC\_MAX</sub> at
- specified I<sub>CC</sub>. Please refer to the loadline specifications in [Section 2.](#page-14-0)<br>2. Maximum Power is the highest power the processor will dissipate, regardless of its VID. Maximum Power is
- measured at maximum T<sub>CASE</sub>.<br>3. Thermal Design Power (TDP) should be used for processor thermal solution design targets. TDP is not the m aximum power that the processor can dissipate. TDP is measured at maximum T<sub>CASE</sub>.
- 4. These specifications are based on silicon characterization. 5. Power specifications are defined at all VIDs found in [Table 2-3](#page-19-0). The Quad-Core Intel® Xeon® Processor
- E5300 may be shipped under multiple VIDs for each frequency. 6. FMB, or Flexible Motherboard, guidelines provide a design target for m eeting all planned processor frequency requirem ents.





### <span id="page-87-0"></span>**Figure 6 - 1 .Quad- Core I ntel® Xeon® Processor E5 3 0 0 Series Therm al Profile**

**Notes:**

- 
- 1. Please refer to [Table 6-2](#page-87-1) for discrete points that constitute the thermal profile.<br>2. Refer to the *Quad-Core Intel® Xeon® Processor 5300 Series Thermal/Mechanical Design Guidelines* for system and environm ental im plem entation details.

### <span id="page-87-1"></span>Table 6-2. Quad-Core Intel® Xeon® Processor E5300 Series Thermal Profile Table





#### **Table 6 - 3 . Quad- Core I ntel® Xeon® Processor X5 3 0 0 Series Therm al Specifications**



#### **Notes:**

- 1. These values are specified at V<sub>CC\_MAX</sub> for all processor frequencies. Systems must be designed to ensure the processor is not to be subjected to any static V<sub>CC</sub> and I<sub>CC</sub> combination wherein V<sub>CC</sub> exceeds V<sub>CC\_MAX</sub> at specified  $I_{CC}$ . Please refer to the loadline specifications in [Section 2.](#page-14-0)
- 2. Maximum Power is the highest power the processor will dissipate, regardless of its VID. Maximum Power is
- measured at maximum T<sub>CASE</sub>.<br>3. Thermal Design Power (TDP) should be used for processor thermal solution design targets. TDP is not the m aximum power that the processor can dissipate. TDP is measured at maximum T<sub>CASE</sub>.
- 4. These specifications are based on silicon characterization.<br>5. Power specifications are defined at all VIDs found in Table Fower specifications are defined at all VIDs found in [Table 2-3](#page-19-0). The Quad-Core Intel® Xeon® Processor
- X5300 Series m ay be shipped under m ultiple VI Ds for each frequency. 6. FMB, or Flexible Motherboard, guidelines provide a design target for m eeting all planned processor frequency requirem ents.

#### <span id="page-88-0"></span>**Figure 6 - 2 .Quad- Core I ntel® Xeon® Processor X5 3 0 0 Series Therm al Profiles**



# **Notes:**

- 1. Quad-Core I ntel® Xeon® Processor X5300 Series Therm al Profile A is representative of a volum etrically unconstrained platform . Please refer to [Table 6-4](#page-89-0) for discrete points that constitute the therm al profile.
- 2. I m plem entation of Quad-Core I ntel® Xeon® Processor X5300 Series Therm al Profile A should result in virtually no TCC activation. Furthermore, utilization of thermal solutions that do not meet processor Quad-Core I ntel® Xeon® Processor X5300 Series Therm al Profile A will result in increased probability of TCC activation and may incur measurable performance loss. (See [Section 6.3](#page-95-0) for details on TCC activation).
- 3. Quad-Core Intel® Xeon® Processor X5300 Series Thermal Profile B is representative of a volumetrically constrained platform. Please refer to [Table 6-5](#page-89-1) for discrete points that constitute the thermal profile. Implementation of Thermal Profile B will result in increased probability of TCC activation and measurable
- perform ance loss. Furtherm ore, utilization of therm al solutions that do not m eet Therm al Profile B do not
- meet the processor's thermal specifications and may result in permanent damage to the processor.<br>5. Refer to the Quad-Core Intel® Xeon® Processor 5300 Series Thermal/Mechanical Design Guidelines for system and environmental implementation details.





100 59.6 105 60.5 110 61.3 115 62.2 120 63.0

### <span id="page-89-0"></span>Table 6-4. Quad-Core Intel<sup>®</sup> Xeon<sup>®</sup> Processor X5300 Series Thermal Profile A Table

### <span id="page-89-1"></span>Table 6-5. Quad-Core Intel® Xeon® Processor X5300 Series Thermal Profile B Table





#### **Table 6 - 6 . Quad- Core I ntel® Xeon® Processor X5 3 6 5 Series Therm al Specifications** Г



**Notes:**

8.

- 1. These values are specified at V<sub>CC\_MAX</sub> for all processor frequencies. Systems must be designed to ensure the processor is not to be subjected to any static V<sub>CC</sub> and I<sub>CC</sub> combination wherein V<sub>CC</sub> exceeds V<sub>CC\_MAX</sub> a
- specified I<sub>CC</sub>. Please refer to the loadline specifications in [Section 2.](#page-14-0)<br>2. Maximum Power is the highest power the processor will dissipate, regardless of its VID. Maximum Power is
- measured at maximum T<sub>CASE</sub>.<br>3. Thermal Design Power (TDP) should be used for processor thermal solution design targets. TDP is not the m aximum power that the processor can dissipate. TDP is measured at maximum T<sub>CASE</sub>.
- 4. These specifications are based on silicon characterization.
- 5. Power specifications are defined at all VI Ds found in [Table 2-3](#page-19-0). The Quad-Core I ntel® Xeon® Processor
- L5300 Series may be shipped under multiple VIDs for each frequency.
- 6. FMB, or Flexible Motherboard, guidelines provide a design target for meeting all planned processor frequency requirem ents. 7.

#### <span id="page-90-0"></span>**Figure 6 - 3 . Quad- Core I ntel® Xeon® Processor X5 3 6 5 Series Therm al Profile** Ţ



#### **Notes:**

3. 4. 5.

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- 1. Please refer to [Table 6-7](#page-91-0) for discrete points that constitute the thermal profile.<br>2. Refer to the *Quad-Core Intel® Xeon® Processor 5300 Series Thermal/Mechanical Design Guidelines* for system and environm ental im plem entation details.





#### <span id="page-91-0"></span>**Table 6 - 7 . Quad- Core I ntel® Xeon® Processor X5 3 6 5 Series Therm al Profile ( Sheet 1 of**  T

### **Table 6 - 8 . Quad- Core I ntel® Xeon® Processor L5 3 0 0 Series Therm al Specifications**



**Notes:**

- 1. These values are specified at  $V_{CC\_MAX}$  for all processor frequencies. Systems must be designed to ensure the processor is not to be subjected to any static V<sub>CC</sub> and I<sub>CC</sub> combination wherein V<sub>CC</sub> exceeds V<sub>CC\_MAX</sub> at<br>specified I<sub>CC</sub>. Please refer to the loadline specifications in [Section 2.](#page-14-0)
- 2. Maximum Power is the highest power the processor will dissipate, regardless of its VID. Maximum Power is measured at maximum T<sub>CASE</sub>.<br>3. Thermal Design Power (TDP) should be used for processor thermal solution design targets. TDP is not the

m aximum power that the processor can dissipate. TDP is measured at maximum  $T_{\text{CASE}}$ .

4. These specifications are based on silicon characterization.<br>5. Power specifications are defined at all VIDs found in Table

- 5. Power specifications are defined at all VI Ds found in [Table 2-3](#page-19-0). The Quad-Core I ntel® Xeon® Processor L5300 Series may be shipped under multiple VIDs for each frequency.
- 6. FMB, or Flexible Motherboard, guidelines provide a design target for m eeting all planned processor frequency requirements.



<span id="page-92-0"></span>



#### **Notes:**

<span id="page-92-1"></span>6.2

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1. Please refer to [Table 6-9](#page-92-1) for discrete points that constitute the thermal profile.<br>2. Refer to the *Quad-Core Intel® Xeon® Processor 5300 Series Thermal/Mechanical Design Guidelines for* system and environm ental im plem entation details.

#### **Table 6 - 9 . Quad- Core I ntel® Xeon® Processor L5 3 0 0 Series Therm al Profile**



### **Table 6 - 1 0 .Quad- Core I ntel® Xeon® Processor L5 3 1 8 Therm al Specifications**



**Notes:**

1. These values are specified at V<sub>CC\_MAX</sub> for all processor frequencies. Systems must be designed to ensure the processor is not to be subjected to any static V<sub>CC</sub> and I<sub>CC</sub> combination wherein V<sub>CC</sub> exceeds V<sub>CC\_MAX</sub> a

specified I<sub>CC</sub>. Please refer to the loadline specifications in [Section 2.](#page-14-0)<br>2. Maximum Power is the highest power the processor will dissipate, regardless of its VID. Maximum Power is measured at maximum  $T_{CASE}$ .



- 3. Therm al Design Power (TDP) should be used for processor therm al solution design targets. TDP is not the m aximum power that the processor can dissipate. TDP is measured at maximum  $T_{CASE}$ .
- 4. These specifications are based on silicon characterization.<br>5. Power specifications are defined at all VIDs found in Table
- 5. Power specifications are defined at all VI Ds found in [Table 2-3](#page-19-0). The Quad-Core I ntel® Xeon® Processor
- L5300 Series m ay be shipped under m ultiple VI Ds for each frequency.
- 6. FMB, or Flexible Motherboard, guidelines provide a design target for m eeting all planned processor frequency requirements.

<span id="page-93-0"></span>**Figure 6 - 5 . Quad- Core I ntel® Xeon® Processor L5 3 1 8 Therm al Profile**



#### **Notes:**

- 1. Please refer to [Table 6-11](#page-94-0) and [Table 6-12](#page-94-1) for discrete points that constitute the thermal profile.<br>2. Refer to the Quad-Core Intel® Xeon® Processor L5318 Thermal/Mechanical Design Guidelines
- Refer to the Quad-Core Intel® Xeon® Processor L5318 Thermal/Mechanical Design Guidelines for system and environmental implementation details.
- 3. The Nominal Thermal Profile must be used for all normal operating conditions, or for products that do not require NEBS Level 3 com pliance.
- 4. The Short-Term Therm al Profile m ay only be used for short-term excursions to higher am bient operating tem peratures, not to exceed 96 hours per instance, 360 hours per year, and a m axim um of 15 instances per year, as compliant with NEBS Level 3.
- 5. Implementation of either thermal profile should result in virtually no TCC activation.<br>6. Iltilization of a thermal solution that exceeds the Short-Term Thermal Profile, or whi
- 6. Utilization of a therm al solution that exceeds the Short-Term Therm al Profile, or which operates at the Short-Term Thermal Profile for a duration longer than the limits specified in Note 3 above, do not meet the<br>processor's thermal specifications and may result in permanent damage to the processor.

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### <span id="page-94-0"></span>**Table 6 - 1 1 . Quad- Core I ntel® Xeon® Processor L5 3 1 8 Nom inal Therm al Profile**



### <span id="page-94-1"></span>**Table 6 - 1 2 . Quad- Core I ntel® Xeon® Processor L5 3 1 8 Short Term Therm al Profile**



## **6 .2 .1 Therm al Metrology**

The minimum and maximum case temperatures (T $_{\mathsf{CASE}}$ ) are specified in [Table 6-1](#page-86-0), through [Table 6-7](#page-91-0) and are measured at the geometric top center of the processor integrated heat spreader (IHS). [Figure 6-6](#page-95-1) illustrates the location where  ${\sf T}_{\sf CASE}$ 



temperature measurements should be made. For detailed guidelines on temperature measurement methodology, refer to the Quad-Core Intel® Xeon® Processor 5300 Series Thermal/ Mechanical Design Guidelines

### <span id="page-95-1"></span>**Figure 6-6.** Case Temperature (T<sub>CASE</sub>) Measurement Location



**Note:** Figure is not to scale and is for reference only.

# <span id="page-95-0"></span>**6 .3 Processor Therm al Features**

### **6 .3 .1 Therm al Monitor Features**

Quad-Core Intel® Xeon® Processor 5300 Series provide two thermal monitor features, Thermal Monitor (TM1) and Enhanced Therm al Monitor (TM2). The TM1 and TM2 must both be enabled in BIOS for the processor to be operating within specifications. When both are enabled, TM2 will be activated first and TM1 will be added if TM2 is not effective.

### **6 .3 .2 Therm al Monitor ( TM1 )**

The Thermal Monitor (TM1) feature helps control the processor tem perature by activating the Therm al Control Circuit (TCC) when the processor silicon reaches its m aximum operating tem perature. The TCC reduces processor power consum ption as needed by m odulating (starting and stopping) the internal processor core clocks. The tem perature at which Therm al Monitor activates the therm al control circuit is not user T



configurable and is not software visible. Bus traffic is snooped in the normal manner, and interrupt requests are latched (and serviced during the time that the clocks are on) while the TCC is active.

When the TM1 is enabled, and a high temperature situation exists (that is, TCC is active), the clocks will be modulated by alternately turning off and on at a duty cycle specific to the processor (typically 30 - 50%). Cycle times are processor speed dependent and will decrease as processor core frequencies increase. A small amount of hysteresis has been included to prevent rapid active/ inactive transitions of the TCC when the processor temperature is near its maximum operating temperature. Once the tem perature has dropped below the m axim um operating tem perature, and the hysteresis timer has expired, the TCC goes inactive and clock modulation ceases.

With therm al solutions designed to the Quad-Core I ntel® Xeon® Processor E5300 Therm al Profile, the Quad-Core I ntel® Xeon® Processor L5300 Series Thermal Profile, Quad-Core I ntel® Xeon® Processor X5365 Series Therm al Profile, or Quad-Core Intel® Xeon® Processor X5300 Series Thermal Profile A it is anticipated that the TCC would only be activated for very short periods of time when running the most power intensive applications. The processor perform ance im pact due to these brief periods of TCC activation is expected to be so minor that it would be immeasurable. A thermal solution that is designed to Quad-Core I ntel® Xeon® Processor X5300 Series Thermal Profile B m ay cause a noticeable perform ance loss due to increased TCC activation. Thermal Solutions that exceed Thermal Profile B will exceed the maximum temperature specification and affect the long-term reliability of the processor. In addition, a thermal solution that is significantly under designed may not be capable of cooling the processor even when the TCC is active continuously Refer to the Quad-Core Intel® Xeon® Processor 5300 Series Thermal/ Mechanical Design Guidelines for information on designing a therm al solution.

The duty cycle for the TCC, when activated by the TM1, is factory configured and cannot be modified. The TM1 does not require any additional hardware, software drivers, or interrupt handling routines.

### **6 .3 .3 Therm al Monitor 2**

The Quad-Core I ntel® Xeon® Processor 5300 Series adds support for an Enhanced Therm al Monitor capability known as Therm al Monitor 2 (TM2). This m echanism provides an efficient m eans for lim iting the processor temperature by reducing the power consumption within the processor. TM2 requires support for dynamic VID transitions in the platform .

When TM2 is enabled, and a high temperature situation is detected, the Thermal Control Circuit (TCC) will be activated for all processor cores. The TCC causes the processor to adjust its operating frequency (via the bus m ultiplier) and input voltage (via the VID signals). This combination of reduced frequency and VID results in a reduction to the processor power consumption.

A processor enabled for TM2 includes two operating points, each consisting of a specific operating frequency and voltage, which is identical for both processor dies. The first operating point represents the normal operating condition for the processor. Under this condition, the core-frequency-to-system -bus multiplier utilized by the processor is that contained in the CLOCK\_FLEX\_MAX MSR and the VID that is specified in [Table 2-3.](#page-19-0)

The second operating point consists of both a lower operating frequency and voltage. The lowest operating frequency is determined by the lowest supported bus ratio (1/6 for the Quad-Core Intel® Xeon® Processor 5300 Series). When the TCC is activated, the processor autom atically transitions to the new frequency. This transition occurs



rapidly, on the order of 5 µs. During the frequency transition, the processor is unable to service any bus requests, and consequently, all bus traffic is blocked. Edge-triggered interrupts will be latched and kept pending until the processor resum es operation at the new frequency.

Once the new operating frequency is engaged, the processor will transition to the new core operating voltage by issuing a new VID code to the voltage regulator. The voltage regulator must support dynamic VID steps in order to support Thermal Monitor 2. During the voltage change, it will be necessary to transition through multiple VID codes to reach the target operating voltage. Each step will be one VID table entry (see [Table 2-3\)](#page-19-0). The processor continues to execute instructions during the voltage transition. Operation at the lower voltage reduces the power consum ption of the processor.

A sm all am ount of hysteresis has been included to prevent rapid active/ inactive transitions of the TCC when the processor tem perature is near its m axim um operating temperature. Once the temperature has dropped below the maximum operating temperature, and the hysteresis timer has expired, the operating frequency and voltage transition back to the normal system operating point. Transition of the VID code will occur first, in order to insure proper operation once the processor reaches its norm al operating frequency. Refer to [Figure 6-7](#page-97-0) for an illustration of this ordering.



### <span id="page-97-0"></span>**Figure 6-7. Thermal Monitor 2 Frequency and Voltage Ordering**

The PROCHOT# signal is asserted when a high tem perature situation is detected, regardless of whether TM1 or TM2 is enabled.

### **6 .3 .4 On- Dem and Mode**

The processor provides an auxiliary m echanism that allows system software to force the processor to reduce its power consum ption. This mechanism is referred to as "On-Dem and" m ode and is distinct from the Thermal Monitor 1 and Thermal Monitor 2 features. On-Demand mode is intended as a means to reduce system level power consum ption. System s utilizing the Quad-Core I ntel® Xeon® Processor 5300 Series must not rely on software usage of this mechanism to limit the processor temperature. If bit 4 of the IA32\_CLOCK\_MODULATION MSR is set to a '1', the processor will im mediately reduce its power consumption via modulation (starting and stopping) of the internal core clock, independent of the processor temperature. When using On-Dem and m ode, the duty cycle of the clock m odulation is programmable via bits 3: 1 of



the same IA32\_CLOCK\_MODULATION MSR. In On-Demand mode, the duty cycle can be programmed from 12.5% on/ 87.5% off to 87.5% on/ 12.5% off in 12.5% increments. On-Demand mode may be used in conjunction with the Therm al Monitor; however, if the system tries to enable On-Demand mode at the same time the TCC is engaged, the factory configured duty cycle of the TCC will override the duty cycle selected by the On-Demand mode.

### **6 .3 .5 PROCHOT# Signal**

<span id="page-98-0"></span>An external signal, PROCHOT# (processor hot) is asserted when the processor die tem perature of any processor cores has reached its factory configured trip point. I f Thermal Monitor is enabled (note that Therm al Monitor m ust be enabled for the processor to be operating within specification), the TCC will be active when PROCHOT# is asserted. The processor can be configured to generate an interrupt upon the assertion or de-assertion of PROCHOT#. Refer to the Intel® 64 and IA-32 Architectures Software Developer's Manual and the Conroe and Woodcrest Processor Fam ily BI OS Writer's Guide for specific register and programming details.

PROCHOT# is designed to assert at or a few degrees higher than maximum  $T_{CASE}$  (as specified by Therm al Profile A) when dissipating TDP power, and cannot be interpreted as an indication of processor case tem perature. This tem perature delta accounts for processor package, lifetime and manufacturing variations and attempts to ensure the Thermal Control Circuit is not activated below maximum  $T_{\text{CASE}}$  when dissipating TDP power. There is no defined or fixed correlation between the PROCHOT# trip tem perature, or the case tem perature. Therm al solutions m ust be designed to the processor specifications and cannot be adjusted based on experim ental m easurem ents of T<sub>CASE</sub>, or PROCHOT#.

### **6 .3 .6 FORCEPR# Signal**

The FORCEPR# (force power reduction) input can be used by the platform to cause the Quad-Core Intel® Xeon® Processor 5300 Series to activate the TCC. If the processor supports Therm al Monitor 2 (TM2), and has Therm al Monitor 2 and Therm al Monitor (TM) properly enabled, assertion of the FORCEPR# signal will immediately activate Thermal Monitor 2. If the processor does not support Thermal Monitor 2, but has Therm al Monitor properly enabled, FORCEPR# signal assertion will cause Therm al Monitor to become active. Please refer to the Quad-Core Intel® Xeon® Processor 5300 Series NDA Specification Update to determine which processors support TM2 and Conroe and Woodcrest Processor Family BI OS Writer's Guide for details on enabling these capabilities. Assertion of the FORCEPR# signal will activate TCC for all processor cores. The TCC will rem ain active until the system deasserts FORCEPR# .

FORCEPR# is an asynchronous input, which can be employed to thermally protect other system components. To use the voltage regulator (VR) as an example, TCC circuit activation will reduce the current consum ption of the processor and the corresponding tem perature of the VR.

It should be noted that assertion of FORCEPR# does not automatically assert PROCHOT#. As mentioned previously, the PROCHOT# signal is asserted when a high temperature situation is detected. A minimum pulse width of 500 µs is recommended when FORCEPR# is asserted by the system. Sustained activation of the FORCEPR# signal may cause noticeable platform performance degradation.

Refer to the appropriate platform design guidelines for details on implem enting the FORCEPR# signal feature.



## **6 .3 .7 THERMTRI P# Signal**

Regardless of whether or not TM1 or TM2 is enabled, in the event of a catastrophic cooling failure, the processor will automatically shut down when the silicon has reached an elevated temperature (refer to the THERMTRI P# definition in [Table 5-1](#page-76-0)). At this point, the FSB signal THERMTRIP# will go active and stay active as described in [Table 5-1.](#page-76-0) THERMTRIP# activation is independent of processor activity and does not generate any bus cycles. Intel also recommends the removal of  $V_{TT}$ .

# <span id="page-99-1"></span>**6 .4 Platform Environm ent Control I nterface ( PECI )**

### **6 .4 .1 I ntroduction**

<span id="page-99-0"></span>PECI offers an interface for thermal monitoring of Intel processor and chipset components. It uses a single wire, thus alleviating routing congestion issues. [Figure 6-8](#page-99-2) shows an example of the PECI topology in a system with Quad-Core Intel® Xeon® Processor 5300 Series. PECI uses CRC checking on the host side to ensure reliable transfers between the host and client devices. Also, data transfer speeds across the PECI interface are negotiable within a wide range (2 Kbps to 2 Mbps). The PECI interface on Quad-Core Intel® Xeon® Processor 5300 Series is disabled by default and must be enabled through BIOS. More information on this can be found in the Conroe and Woodcrest Processor Fam ily BI OS Writer's Guide.

<span id="page-99-2"></span>



### **6 .4 .1 .1 TCONTROL and TCC Activation on PECI - Based System s**

Fan speed control solutions based on PECI utilize a  $T_{\text{CONTROL}}$  value stored in the processor I A32\_TEMPERATURE\_TARGET MSR. This MSR uses the same offset temperature format as PECI, though it contains no sign bit. Thermal management devices should infer the  $T_{\text{COMTRO}}$  value as negative. Thermal management algorithms should utilize the relative temperature value delivered over PECI in conjunction with the MSR value to control or optimize fan speeds. [Figure 6-9](#page-100-0) shows a conceptual fan control diagram using PECI temperatures.





#### <span id="page-100-0"></span>**Figure 6 - 9 . Conceptual Fan Control Diagram For A PECI - Based Platform**

### **6 .4 .1 .2 Processor Therm al Data Sam ple Rate and Filtering**

The DTS provides an improved capability to monitor device hot spots, which inherently leads to more varying temperature readings over short time intervals. The DTS sample interval range can be modified, and a data filtering algorithm can be activated to help moderate this. The DTS sample interval range is 82 ms (default) to 20 ms (max). This value can be set in BIOS.

To reduce the sample rate requirements on PECI and improve thermal data stability vs. time the processor DTS also implem ents an averaging algorithm that filters the incom ing data. This is an alpha-beta filter with coefficients of 0.5, and is expressed m athem atically as: Current filtered temp = (Previous filtered temp / 2) + (new\_sensor\_temp  $/ 2$ ). This filtering algorithm is fixed and cannot be changed. It is on by default and can be turned off in BIOS.

Host controllers should utilize the min/ max sample times to determine the appropriate sample rate based on the controller's fan control algorithm and targeted response rate. The key items to take into account when settling on a fan control algorithm are the DTS sample rate, whether the tem perature filter is enabled, how often the PECI host will poll the processor for tem perature data, and the rate at which fan speed is changed. Depending on the designer's specific requirem ents the DTS sam ple rate and alpha-beta filter may have no effect on the fan control algorithm.

### **6 .4 .2 PECI Specifications**

### **6 .4 .2 .1 PECI Device Address**

The PECI device address for socket 0 is 0x30 and socket 1 is 0x31. Please note that each address also supports two domains (Domain 0 and Domain 1). For more information on PECI domains, please refer to the Platform Environment Control Interface Specification.



### **6 .4 .2 .2 PECI Com m and Support**

PECI command support is covered in detail in Platform Environment Control Interface Specification. Please refer to this document for details on supported PECI command function and codes

### **6 .4 .2 .3 PECI Fault Handling Requirem ents**

PECI is largely a fault tolerant interface, including noise immunity and error checking im provements over other com patible industry standard interfaces. The PECI client is as reliable as the device that it is em bedded within, and thus given operating conditions that fall under the specification, the PECI client will always respond to requests and the protocol itself can be relied upon to detect any transmission failures. There are, however, certain scenarios where PECI is known to be unresponsive.

Prior to a power on RESET# and during RESET# assertion, PECI is not guaranteed to provide reliable therm al data. System designs should im plem ent a default power-on condition that ensures proper processor operation during the time frame when reliable data is not available via PECI .

To protect platform s from potential operational or safety issues due to an abnormal condition on PECI , the PECI host controller should take action to protect the system from possible damage. It is recommended that the PECI host controller take appropriate action to protect the client processor device if valid temperature readings have not been obtained in response to three consecutive gettemp()s or for a one second time interval. The PECI host controller may also implement an alert to software in the event of a critical or continuous fault condition.

### **6 .4 .2 .4 PECI GetTem p0 ( ) and GetTem p1 ( ) Error Code Support**

The error codes supported for the processor GetTemp0() and GetTemp1() command are listed in [Table 6-13](#page-101-0) below:

### <span id="page-101-0"></span>**Table 6 - 1 3 . GetTem p0 ( ) and GetTem p1 ( ) Error Codes**



**§**



# **7 Features**

# **7 .1 Pow er- On Configuration Options**

<span id="page-102-0"></span>Several configuration options can be configured by hardware. Quad-Core Intel® Xeon® Processor 5300 Series sam ple its hardware configuration at reset, on the active-toinactive transition of RESET# . For specifics on these options, please refer to [Table 7-1](#page-105-0).

The sampled information configures the processor for subsequent operation. These configuration options cannot be changed except by another reset. All resets reconfigure the processor, for reset purposes, the processor does not distinguish between a "warm " reset (PWRGOOD signal rem ains asserted) and a "power-on" reset.

### **Table 7 - 1 . Pow er- On Configuration Option Lands**



#### **Notes:**

1. Asserting this signal during RESET# will select the corresponding option.<br>2. Address lands not identified in this table as configuration options should

2. Address lands not identified in this table as configuration options should not be asserted during RESET#.<br>3. Bequires de-assertion of PWRGOOD

Requires de-assertion of PWRGOOD.

Disabling of any of the cores within the Quad-Core I ntel® Xeon® Processor 5300 Series must be handled by configuring the EXT\_CONFIG Model Specific Register (MSR). This MSR will allow for the disabling of a single core per die within the Quad-Core I ntel® Xeon® Processor 5300 Series package. Additional details can be found in the Conroe and Woodcrest Processor Family BI OS Writer's Guide.

# **7 .2 Clock Control and Low Pow er States**

Quad-Core I ntel® Xeon® Processor 5300 Series support the Extended HALT state (also referred to as C1E) in addition to the HALT state and Stop-Grant state to reduce power consum ption by stopping the clock to internal sections of the processor, depending on each particular state. See [Figure 7-1](#page-105-0) for a visual representation of the processor low power states. The Extended HALT state is a lower power state than the HALT state or Stop Grant state.

**The Extended HALT state m ust be enabled via the BI OS for the processor to rem ain w ithin its specifications.** Refer to the Conroe and Woodcrest Processor Family BIOS Writer's Guide. For processors that are already running at the lowest bus to core frequency ratio for its nom inal operating point, the processor will transition to the HALT state instead of the Extended HALT state.

The Stop Grant state requires chipset and BIOS support on multiprocessor systems. In a multiprocessor system, all the STPCLK# signals are bussed together, thus all processors are affected in unison. When the STPCLK# signal is asserted, the processor enters the Stop Grant state, issuing a Stop Grant Special Bus Cycle (SBC) for each processor. The chipset needs to account for a variable num ber of processors asserting



the Stop Grant SBC on the bus before allowing the processor to be transitioned into one of the lower processor power states. Refer to the applicable chipset specification and the Conroe and Woodcrest Processor Family BIOS Writer's Guide for more information.

### **7 .2 .1 Norm al State**

This is the norm al operating state for the processor.

### **7 .2 .2 HALT or Extended HALT State**

The Extended HALT state (C1E) is enabled via the BIOS. Refer to the Conroe and Woodcrest Processor Family BI OS Writer's Guide. **The Extended HALT state m ust be enabled for the processor to rem ain w ithin its specifications.** The Extended HALT state requires support for dynamic VID transitions in the platform.

### **7 .2 .2 .1 HALT State**

HALT is a low power state entered when the processor has executed the HALT or MWAIT instruction. When one of the processor cores execute the HALT or MWAIT instruction, that processor core is halted; however, the other processor continues norm al operation. The processor will transition to the Norm al state upon the occurrence of SMI#, BINIT#, INIT#, LINT[1:0] (NMI, INTR), or an interrupt delivered over the front side bus. RESET# will cause the processor to immediately initialize itself.

The return from a System Management Interrupt (SMI) handler can be to either Normal Mode or the HALT state. See the Intel® 64 and IA-32 Intel® Architecture Software Developer's Manual, Volume III: System Programming Guide for more inform ation.

The system can generate a STPCLK# while the processor is in the HALT state. When the system deasserts STPCLK#, the processor will return execution to the HALT state.

While in HALT state, the processor will process front side bus snoops and interrupts.

### **7 .2 .2 .2 Extended HALT State**

Extended HALT state is a low power state entered when all four processor cores have executed the HALT or MWAIT instructions and Extended HALT state has been enabled via the BI OS. When one of the processor cores executes the HALT instruction, that processor core is halted; however, the other processor cores continue norm al operation. The Extended HALT state is a lower power state than the HALT state or Stop Grant state. The Extended HALT state must be enabled for the processor to remain within its specifications.

The processor will autom atically transition to a lower core frequency and voltage operating point before entering the Extended HALT state. Note that the processor FSB frequency is not altered; only the internal core frequency is changed. When entering the low power state, the processor will first switch to the lower bus to core frequency ratio and then transition to the lower voltage (VID).

While in the Extended HALT state, the processor will process bus snoops. The processor exits the Extended HALT state when a break event occurs. When the processor exits the Extended HALT state, it will first transition the VID to the original value and then change the bus to core frequency ratio back to the original value.



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#### Table 7-2. Extended HALT Maximum Power



#### **Notes:**

1. These specifications are based on silicon characterization.<br>2. Processors running in the lowest bus ratio will enter the HALT state when the processor has executed the<br> HALT and MWAIT instruction since the operating point. Values represent SKUs with Extended HALT state (25W/30W) and without Extended HALT<br>state (34W).<br>3. G-0 stepping SKUs with Extended HALT state are specified at T<sub>CASE</sub> = 40°C.



<span id="page-105-0"></span>**Figure 7-1. Stop Clock State Machine** 



### **7 .2 .3 Stop- Grant State**

When the STPCLK# pin is asserted, the Stop-Grant state of the processor is entered 20 bus clocks after the response phase of the processor issued Stop Grant Acknowledge special bus cycle. The Quad-Core I ntel® Xeon® Processor 5300 Series will issue two Stop Grant Acknowledge special bus cycles, once for each die. Once the STPCLK# pin has been asserted, it may only be deasserted once the processor is in the Stop Grant state. All processor cores will enter the Stop-Grant state once the STPCLK# pin is asserted. Additionally, all processor cores must be in the Stop Grant state before the deassertion of STPCLK# .

Since the AGTL+ signal pins receive power from the front side bus, these pins should not be driven (allowing the level to return to  $V<sub>TT</sub>$ ) for minimum power drawn by the termination resistors in this state. In addition, all other input pins on the front side bus should be driven to the inactive state.

BINIT# will not be serviced while the processor is in Stop-Grant state. The event will be latched and can be serviced by software upon exit from the Stop Grant state.

RESET# will cause the processor to immediately initialize itself, but the processor will stay in Stop-Grant state. A transition back to the Norm al state will occur with the deassertion of the STPCLK# signal.



A transition to the Grant Snoop state will occur when the processor detects a snoop on the front side bus (see [Section 7.2.4.1\)](#page-106-0).

While in the Stop-Grant state, SMI#, INIT#, BINIT# and LINT[1:0] will be latched by the processor, and only serviced when the processor returns to the Normal state. Only one occurrence of each event will be recognized upon return to the Norm al state.

While in Stop-Grant state, the processor will process snoops on the front side bus and it will latch interrupts delivered on the front side bus.

The PBE# signal can be driven when the processor is in Stop-Grant state. PBE# will be asserted if there is any pending interrupt latched within the processor. Pending interrupts that are blocked by the EFLAGS.IF bit being clear will still cause assertion of PBE# . Assertion of PBE# indicates to system logic that it should return the processor to the Norm al state.

### **7 .2 .4 Extended HALT Snoop or HALT Snoop State, Stop Grant Snoop State**

The Extended HALT Snoop state is used in conjunction with the Extended HALT state. If the Extended HALT state is not enabled in the BI OS, the default Snoop state entered will be the HALT Snoop state. Refer to the sections below for details on HALT Snoop state, Stop Grant Snoop state and Extended HALT Snoop state.

### <span id="page-106-0"></span>**7 .2 .4 .1 HALT Snoop State, Stop Grant Snoop State**

The processor will respond to snoop or interrupt transactions on the front side bus while in Stop-Grant state or in HALT state. During a snoop or interrupt transaction, the processor enters the HALT/ Grant Snoop state. The processor will stay in this state until the snoop on the front side bus has been serviced (whether by the processor or another agent on the front side bus) or the interrupt has been latched. After the snoop is serviced or the interrupt is latched, the processor will return to the Stop-Grant state or HALT state, as appropriate.

### **7 .2 .4 .2 Extended HALT Snoop State**

The Extended HALT Snoop state is the default Snoop state when the Extended HALT state is enabled via the BIOS. The processor will remain in the lower bus to core frequency ratio and VID operating point of the Extended HALT state.

While in the Extended HALT Snoop state, snoops and interrupt transactions are handled the sam e way as in the HALT Snoop state. After the snoop is serviced or the interrupt is latched, the processor will return to the Extended HALT state.

## **7 .3 Enhanced I ntel SpeedStep® Technology**

Quad-Core Intel® Xeon® Processor 5300 Series support Enhanced Intel SpeedStep® Technology. This technology enables the processor to switch between multiple frequency and voltage points, which results in platform power savings. Enhanced Intel SpeedStep Technology requires support for dynamic VID transitions in the platform. Switching between voltage/ frequency states is software controlled. For more configuration details also refer to the Conroe and Woodcrest Processor Family BIOS Writer's Guide.

**Note:** Not all Quad-Core Intel® Xeon® Processor 5300 Series are capable of supporting Enhanced I ntel SpeedStep Technology. More details on which processor frequencies will

**Features**



support this feature will be provided in future releases of the Quad-Core Intel® Xeon® Processor 5300 Series NDA Specification Update when available.

Enhanced I ntel SpeedStep Technology creates processor perform ance states (P-states) or voltage/ frequency operating points. P-states are lower power capability states within the Normal state as shown in [Figure 7-1.](#page-105-0) Enhanced Intel SpeedStep Technology enables real-time dynamic switching between frequency and voltage points. It alters the perform ance of the processor by changing the bus to core frequency ratio and voltage. This allows the processor to run at different core frequencies and voltages to best serve the performance and power requirements of the processor and system . The Quad-Core I ntel® Xeon® Processor 5300 Series have hardware logic that coordinates the requested voltage (VID) between the processor cores. The highest voltage that is requested from the four processor cores is selected for that processor package. Note that the front side bus is not altered; only the internal core frequency is changed. In order to run at reduced power consum ption, the voltage is altered in step with the bus ratio.

The following are key features of Enhanced I ntel SpeedStep Technology:

- Multiple voltage/ frequency operating points provide optim al perform ance at reduced power consumption.
- Voltage/ frequency selection is software controlled by writing to processor MSR's (Model Specific Registers), thus elim inating chipset dependency.
	- $-$  If the target frequency is higher than the current frequency,  $V_{CC}$  is incremented in steps  $(+12.5 \text{ mV})$  by placing a new value on the VID signals and the processor shifts to the new frequency. Note that the top frequency for the processor can not be exceeded.
	- $-$  If the target frequency is lower than the current frequency, the processor shifts to the new frequency and  $V_{CC}$  is then decremented in steps (-12.5 mV) by changing the target VID through the VID signals.

See the Conroe and Woodcrest Processor Family BIOS Writer's Guide for specific information to enable and configure Enhanced Intel SpeedStep Technology in BIOS.

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# **8 Boxed Processor Specifications**

# **8 .1 I ntroduction**

Intel boxed processors are intended for system integrators who build systems from components available through distribution channels. The Quad-Core Intel® Xeon® Processor 5300 Series will be offered as an I ntel boxed processor.

Intel will offer the Quad-Core Intel® Xeon® Processor 5300 Series boxed processor with two heat sink configurations available for each processor frequency: 1U passive/  $3U_{+}$  active combination solution and a 2U passive only solution. The 1U passive/ $3U_{+}$ active com bination solution is based on a 1U passive heat sink with a rem ovable fan that will be pre-attached at shipping. This heat sink solution is intended to be used as either a 1U passive heat sink, or a 3U+ active heat sink. Although the active combination solution with removable fan mechanically fits into a 2U keepout, its use is not recom m ended in that configuration.

The  $1U$  passive/ $3U<sub>+</sub>$  active combination solution in the active fan configuration is primarily designed to be used in a pedestal chassis where sufficient air inlet space is present and strong side directional airflow is not an issue. The 1U passive/ 3U+ active com bination solution with the fan rem oved and the 2U passive therm al solution require the use of chassis ducting and are targeted for use in rack m ount or pedestal servers. The retention solution used for these products is called the Common Enabling Kit, or CEK. The CEK base is compatible with both thermal solutions and uses the same hole locations as the Dual-Core Intel® Xeon® processor 5100 series.

The 1U passive/3U+ active combination solution will utilize a removable fan capable of 4-pin pulse width modulated (PWM) control. Use of a 4-pin PWM controlled active therm al solution helps custom ers m eet acoustic targets in pedestal platform s through the m otherboards's ability to directly control the RPM of the processor heat sink fan. See [Section 8.3](#page-118-0) for more details on fan speed control, and see [Section 6.4](#page-99-0) for more on the PWM and PECI interface along with Digital Thermal Sensors (DTS). [Figure 8-1](#page-108-0) through [Figure 8-3](#page-109-0) are representations of the two heat sink solutions.

#### <span id="page-108-0"></span>**Figure 8 - 1 . Boxed Quad- Core I ntel® Xeon® Processor 5 3 0 0 Series 1 U Passive/ 3 U+ Active Com bination Heat Sink ( W ith Rem ovable Fan)**





#### <span id="page-109-1"></span>**Figure 8 - 2 . Boxed Quad- Core I ntel® Xeon® Processor 5 3 0 0 Series 2 U Passive Heat Sink**



#### <span id="page-109-0"></span>Figure 8-3. 2U Passive Quad-Core Intel<sup>®</sup> Xeon<sup>®</sup> Processor 5300 Series Processor **Therm al Solution ( Exploded View )**



**Note:**

- 1. The heat sinks and fan assem blies represented in [Figure 8-1](#page-108-0), [Figure 8-2,](#page-109-1) and [Figure 8-3](#page-109-0) are for reference only, and m ay not represent the final boxed processor heat sinks. 2. The screws, springs, and standoffs will be captive to the heat sink. This im age shows all of the com ponents
- in an exploded view.
- 3. I t is intended that the CEK spring will ship with the base board and be pre-attached prior to shipping.



# **8 .2 Mechanical Specifications**

This section documents the mechanical specifications of the boxed processor.

## **8 .2 .1 Boxed Processor Heat Sink Dim ensions ( CEK)**

The boxed processor will be shipped with an unattached therm al solution. Clearance is required around the therm al solution to ensure unim peded airflow for proper cooling. The physical space requirements and dimensions for the boxed processor and assem bled heat sink are shown in [Figure 8-4](#page-111-0) through [Figure 8-8](#page-115-0). [Figure 8-9](#page-116-0) through [Figure 8-10](#page-117-0) are the mechanical drawings for the 4-pin board fan header and 4-pin connector used for the active CEK fan heat sink solution.





#### <span id="page-111-0"></span>Figure 8-4. Top Side Board Keepout Zones (Part 1)











**Figure 8-6. Bottom Side Board Keepout Zones** 





### **Figure 8-7. Board Mounting-Hole Keepout Zones**



<span id="page-115-0"></span>Figure 8-8. Volumetric Height Keep-Ins







#### <span id="page-116-0"></span>Figure 8-9. 4-Pin Fan Cable Connector (For Active CEK Heat Sink)





#### <span id="page-117-0"></span>**Figure 8 - 1 0 . 4 - Pin Base Board Fan Header ( For Active CEK Heat Sink)**



## **8 .2 .2 Boxed Processor Heat Sink W eight**

#### **8 .2 .2 .1 Therm al Solution W eight**

The 1U passive/ 3U+ active com bination heat sink solution and the 2U passive heat sink solution will not exceed a mass of 1050 grams. Note that this is per processor, a dual processor system will have up to 2100 grams total m ass in the heat sinks. This large m ass will require a m inim um chassis stiffness to be m et in order to withstand force during shock and vibration.

See [Section 3](#page-44-0) for details on the processor weight.

### **8 .2 .3 Boxed Processor Retention Mechanism and Heat Sink Support ( CEK)**

Baseboards and chassis designed for use by a system integrator should include holes that are in proper alignm ent with each other to support the boxed processor. Refer to the Server System Infrastructure Specification (SSI-EEB 3.6, TEB 2.1 or CEB 1.1). These specification can be found at: http://www.ssiforum.org.

[Figure 8-3](#page-109-0) illustrates the Common Enabling Kit (CEK) retention solution. The CEK is designed to extend air-cooling capability through the use of larger heat sinks with minimal airflow blockage and bypass. CEK retention mechanisms can allow the use of much heavier heat sink masses compared to legacy limits by using a load path directly attached to the chassis pan. The CEK spring on the secondary side of the baseboard provides the necessary com pressive load for the thermal interface m aterial. The baseboard is intended to be isolated such that the dynam ic loads from the heat sink are transferred to the chassis pan via the stiff screws and standoffs. The retention schem e reduces the risk of package pullout and solder joint failures.

All com ponents of the CEK heat sink solution will be captive to the heat sink and will only require a Phillips screwdriver to attach to the chassis pan. When installing the CEK, the CEK screws should be tightened until they will no longer turn easily. This should represent approximately 6-8 inch-pounds of torque. More than that m ay dam age the retention mechanism com ponents.

# <span id="page-118-0"></span>**8 .3 Electrical Requirem ents**

## **8 .3 .1 Fan Pow er Supply ( Active CEK)**

The 4-pin PWM controlled active therm al solution is being offered to help provide better control over pedestal chassis acoustics. This is achieved though m ore accurate measurement of processor die temperature through the processor's Digital Therm al Sensors. Fan RPM is m odulated through the use of an ASI C located on the baseboard, that sends out a PWM control signal to the 4th pin of the connector labeled as Control. This thermal solution requires a constant + 12 V supplied to pin 2 of the active thermal solution and does not support variable voltage control or 3-pin PWM control. See [Table 8-2](#page-119-0) for details on the 4-pin active heat sink solution connectors.

If the 4-pin active fan heat sink solution is connected to an older 3-pin baseboard CPU fan header it will default back to a thermistor controlled mode, allowing compatibility with legacy 3-wire designs. When operating in thermistor controlled mode, fan RPM is autom atically varied based on the TI NLET temperature measured by a thermistor located at the fan inlet of the heat sink solution.

The fan power header on the baseboard must be positioned to allow the fan heat sink power cable to reach it. The fan power header identification and location must be documented in the suppliers platform documentation, or on the baseboard itself. The baseboard fan power header should be positioned within 177.8 mm [7 in.] from the center of the processor socket.

#### **Table 8 - 1 . PW M Fan Frequency Specifications for 4 - Pin Active CEK Therm al Solution**



#### <span id="page-119-0"></span>**Table 8 - 2 . Fan Specifications for 4 - Pin Active CEK Therm al Solution**



**Note:**

1. System board should pull this pin up to Vcc with a resistor

#### **Figure 8 - 1 1 . Fan Cable Connector Pin Out for 4 - Pin Active CEK Therm al Solution**



#### **Table 8 - 3 . Fan Cable Connector Pin Out for 4 - Pin Active CEK Therm al Solution**



**Note:** System board should provide an open drain / open collector for pin 4. Fan will pull this pin up to a specific voltage (5.25V max).

## **8 .3 .2 Boxed Processor Cooling Requirem ents**

As previously stated the boxed processor will be available in two product configurations. Each configuration will require unique design considerations. Meeting the processor's tem perature specifications is also the function of the therm al design of the entire system , and ultim ately the responsibility of the system integrator. The processor tem perature specifications are found in [Section 6](#page-84-0) of this docum ent.



#### **8 .3 .2 .1 1 U Passive/ 3 U+ Active Com bination Heat Sink Solution ( 1 U Rack Passive)**

In the 1U configuration it is assumed that a chassis duct will be implemented to provide a minimum airflow of 15 cfm at 0.38 in. H<sub>2</sub>O (25.5 m $^3$ /hr at 94.6 Pa) of flow im pedance. The duct should be carefully designed to minimize the airflow bypass around the heatsink. It is assumed that a  $40^{\circ}$ C TLA is met. This requires a superior chassis design to limit the  $T_{\text{RISE}}$  at or below 5°C with an external ambient temperature of 35 $^{\circ}$  C. Following these guidelines will allow the designer to meet Quad-Core Intel® Xeon® Processor X5300 Series Therm al Profile and conform to the therm al requirements of the processor.

#### **8 .3 .2 .2 1 U Passive/ 3 U+ Active Com bination Heat Sink Solution ( Pedestal Active)**

The active configuration of the com bination solution is designed to help pedestal chassis users to meet the thermal processor requirements without the use of chassis ducting. It may be still be necessary to implement some form of chassis air guide or air duct to meet the  $T_{LA}$  temperature of 40 $^{\circ}$ C depending on the pedestal chassis layout. Also, while the active thermal solution design will m echanically fit into a 2U volum etric, it may not provide adequate airflow. This is due to the requirement of additional space at the top of the thermal solution to allow sufficient airflow into the heat sink fan. Use of the active configuration in a 2U rackmount chassis is not recommended.

It is recommended that the ambient air temperature outside of the chassis be kept at or below 35°C. The air passing directly over the processor thermal solution should not be preheated by other system components. Meeting the processor's temperature specification is the responsibility of the system integrator.

#### **8 .3 .2 .3 2 U Passive Heat Sink Solution ( 2 U+ Rack or Pedestal)**

In the 2U+ passive configuration it is assumed that a chassis duct will be implemented to provide a minimum airflow of 27 cfm at 0.182 in. H<sub>2</sub>O (45.9 m $^3$ /hr at 45.3 Pa) of flow impedance. The duct should be carefully designed to minimize the airflow bypass around the heatsink. The  $T_{LA}$  temperature of 40 $^{\circ}$ C should be met. This may require the use of superior design techniques to keep  $T_{\text{RISF}}$  at or below 5°C based on an ambient external temperature of 35° C.

# **8 .4 Boxed Processor Contents**

A direct chassis attach method must be used to avoid problems related to shock and vibration, due to the weight of the thermal solution required to cool the processor. The board must not bend beyond specification in order to avoid damage. The boxed processor contains the components necessary to solve both issues. The boxed processor will include the following items:

- Quad-Core Intel® Xeon® Processor 5300 Series
- Unattached heat sink solution
- Four screws, four springs, and four heat sink standoffs (all captive to the heat sink)
- Foam air bypass pad and skirt (included with 1U passive/3U+ active solution)
- Therm al interface m aterial (pre-applied on heat sink)
- Installation and warranty manual
- Intel Inside Logo



The other items listed in [Figure 8-3](#page-109-0) that are required to compete this solution will be shipped with either the chassis or boards. They are as follows:

- CEK Spring (supplied by baseboard vendors)
- Heat sink standoffs (supplied by chassis vendors)

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# **9 Debug Tools Specifications**

Please refer to the Debug Port Design Guide for UP/DP Systems and the appropriate platform design guidelines for inform ation regarding debug tool specifications. [Section 1.3](#page-12-0) provides collateral details.

# **9 .1 Debug Port System Requirem ents**

The Quad-Core I ntel® Xeon® Processor 5300 Series debug port is the com mand and control interface for the In-Target Probe (ITP) debugger. The ITP enables run-time control of the processors for system debug. The debug port, which is connected to the FSB, is a combination of the system, JTAG and execution signals. There are several mechanical, electrical and functional constraints on the debug port that must be followed. The mechanical constraint requires the debug port connector to be installed in the system with adequate physical clearance. Electrical constraints exist due to the mixed high and low speed signals of the debug port for the processor. While the JTAG signals operate at a maximum of 75 MHz, the execution signals operate at the common clock FSB frequency. The functional constraint requires the debug port to use the JTAG system via a handshake and multiplexing scheme.

In general, the information in this chapter may be used as a basis for including all runcontrol tools in Quad-Core I ntel® Xeon® Processor 5300 Series based systems designs including tools from vendors other than Intel.

**Note:** The debug port and JTAG signal chain must be designed into the processor board to utilize the XDP for debug purposes except for interposer solutions.

# **9 .2 Target System I m plem entation**

## **9 .2 .1 System I m plem entation**

Specific connectivity and layout guidelines for the Debug Port are provided in the Debug Port Design Guide for UP/DP Systems and the appropriate platform design guidelines.

# **9 .3 Logic Analyzer I nterface ( LAI )**

I ntel is working with two logic analyzer vendors to provide logic analyzer interfaces (LAIs) for use in debugging Quad-Core Intel® Xeon® Processor 5300 Series systems. Tektronix and Agilent should be contacted to obtain specific inform ation about their logic analyzer interfaces. The following information is general in nature. Specific information must be obtained from the logic analyzer vendor.

Due to the complexity of Quad-Core Intel® Xeon® Processor 5300 Series based m ultiprocessor systems, the LAI is critical in providing the ability to probe and capture FSB signals. There are two sets of considerations to keep in mind when designing a Quad-Core Intel® Xeon® Processor 5300 Series based system that can make use of an LAI: mechanical and electrical.



## **9 .3 .1 Mechanical Considerations**

The LAI is installed between the processor socket and the processor. The LAI plugs into the socket, while the processor plugs into a socket on the LAI . Cabling that is part of the LAI egresses the system to allow an electrical connection between the processor and a logic analyzer. The maximum volume occupied by the LAI, known as the keepout volum e, as well as the cable egress restrictions, should be obtained from the logic analyzer vendor. System designers must make sure that the keepout volume remains unobstructed inside the system. In some cases, it is known that some of the electrolytic capacitors fall inside of the keepout volume for the LAI. In this case, it is necessary to m ove these capacitors to the backside of the board before using the LAI . Additionally, note that it is possible that the keepout volum e reserved for the LAI m ay include different requirements from the space normally occupied by the heatsink. If this is the case, the logic analyzer vendor will provide either a cooling solution as part of the LAI or additional hardware to mount the existing cooling solution.

## **9 .3 .2 Electrical Considerations**

The LAI will also affect the electrical perform ance of the FSB, therefore it is critical to obtain electrical load models from each of the logic analyzer vendors to be able to run system level sim ulations to prove that their tool will work in the system . Contact the logic analyzer vendor for electrical specifications and load m odels for the LAI solution they provide.

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